

# EE 330

# Lecture 17

MOSFET Modeling

# Prelab Announcement

A Pre-Lab will be posted on Canvas for Lab 7

# Exam Schedule

Exam 2 will be given on Friday March 11

Exam 3 will be given on Friday April 15

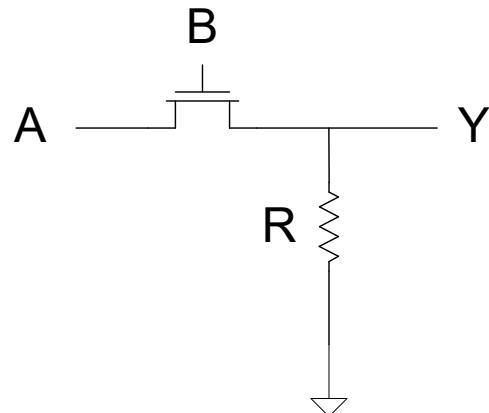
Photo courtesy of the director of the National Institute of Health ( NIH)



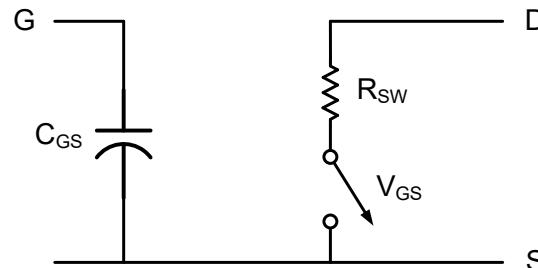
As a courtesy to fellow classmates, TAs, and the instructor

Wearing of masks during lectures and in the laboratories for this course would be appreciated irrespective of vaccination status

# Limitations of Existing MOSFET Models



What is Y when A=B=V<sub>DD</sub>

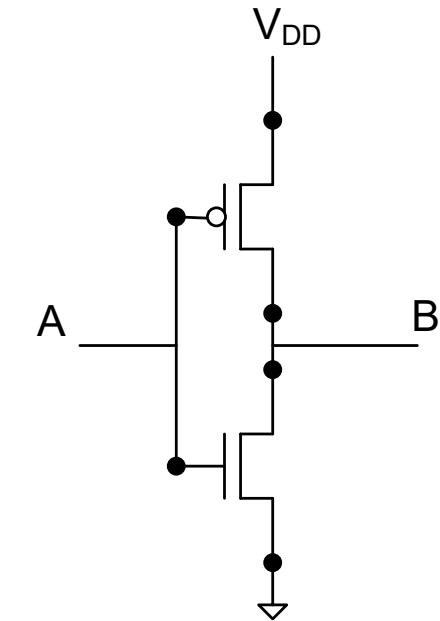


*For minimum-sized devices in a 0.5μ process with V<sub>DD</sub>=5V*

$$C_{GS} \approx 1.5\text{fF}$$

$$R_{sw} \approx \left. \begin{array}{l} 2\text{K}\Omega \text{ n-channel} \\ 6\text{K}\Omega \text{ p-channel} \end{array} \right\}$$

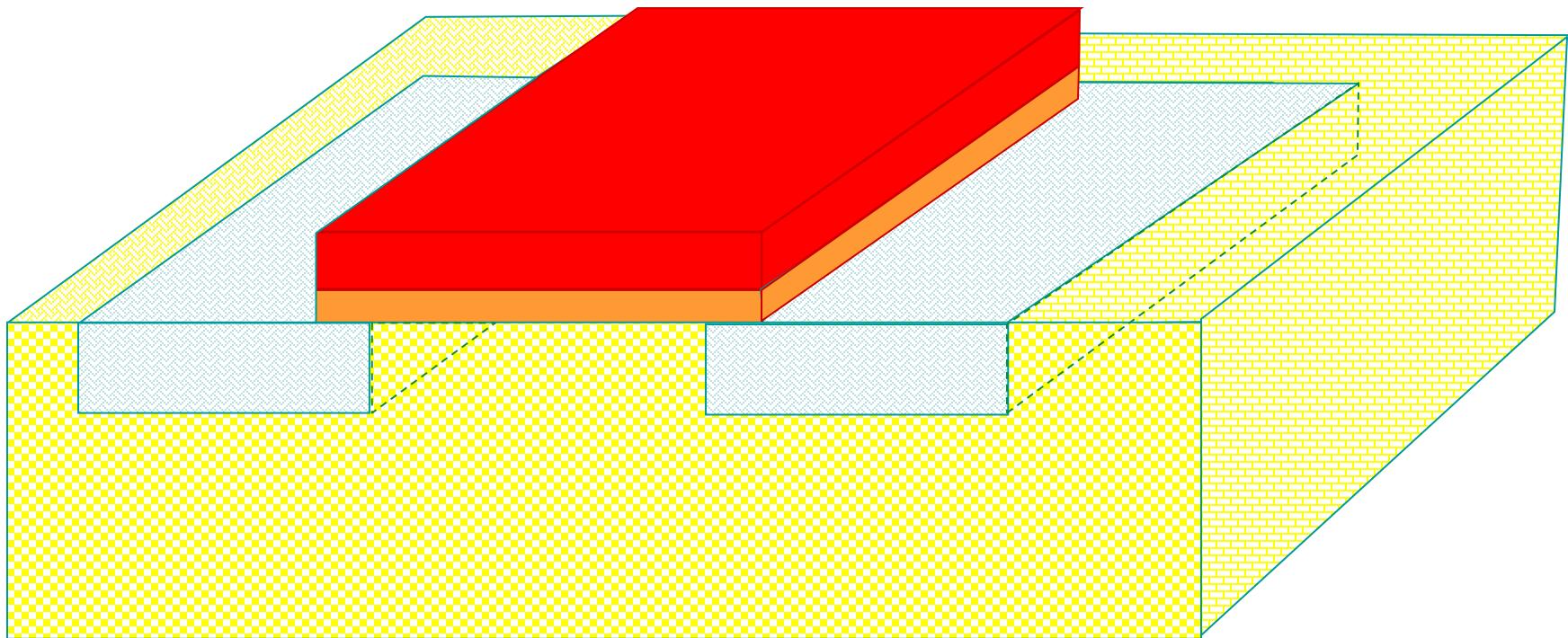
What is R<sub>SW</sub> if MOSFET is not minimum sized?



What is power dissipation if A is stuck at an intermediate voltage?

**Better Model of MOSFET is Needed!**

# n-Channel MOSFET



Poly



n-active

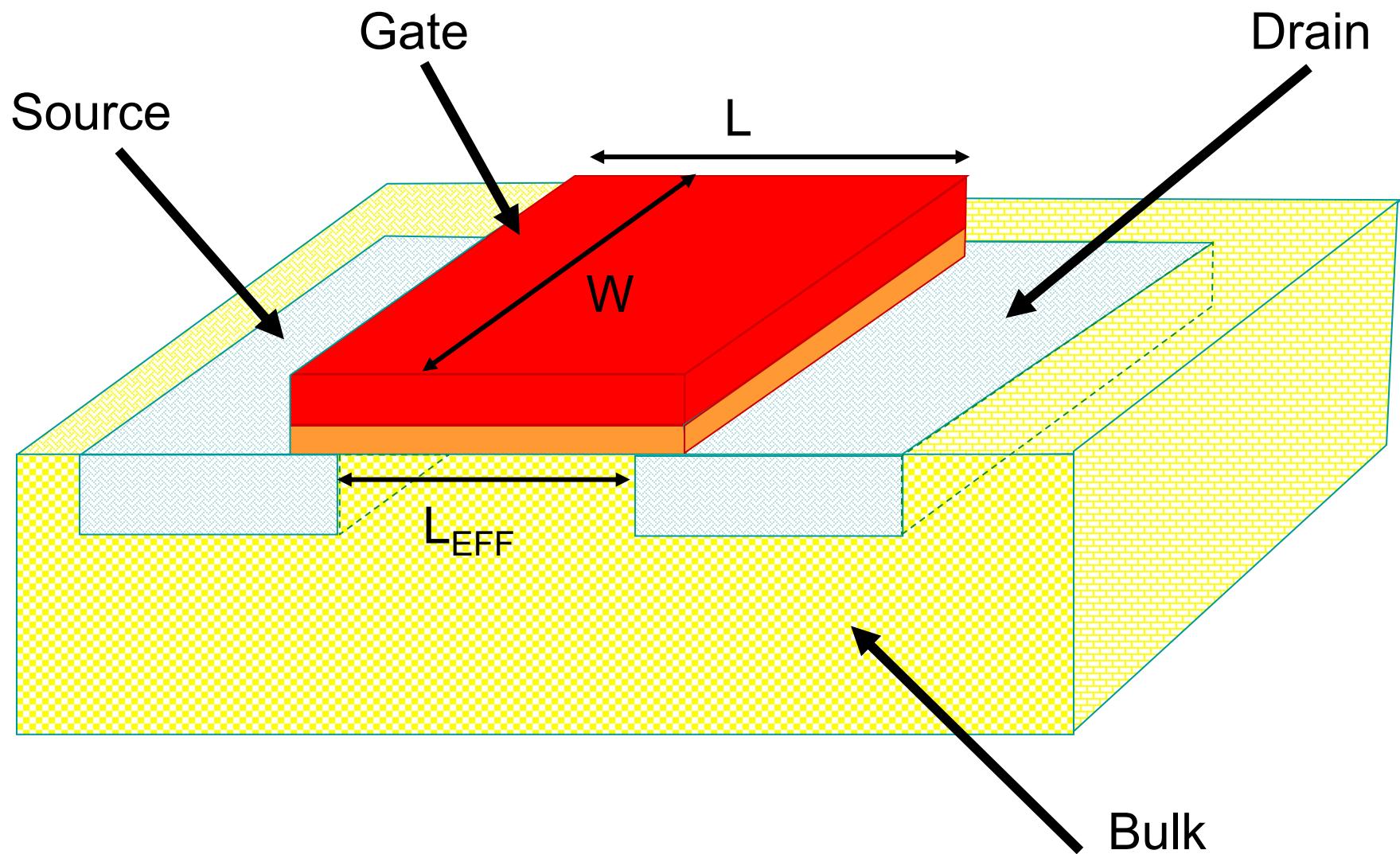


Gate oxide

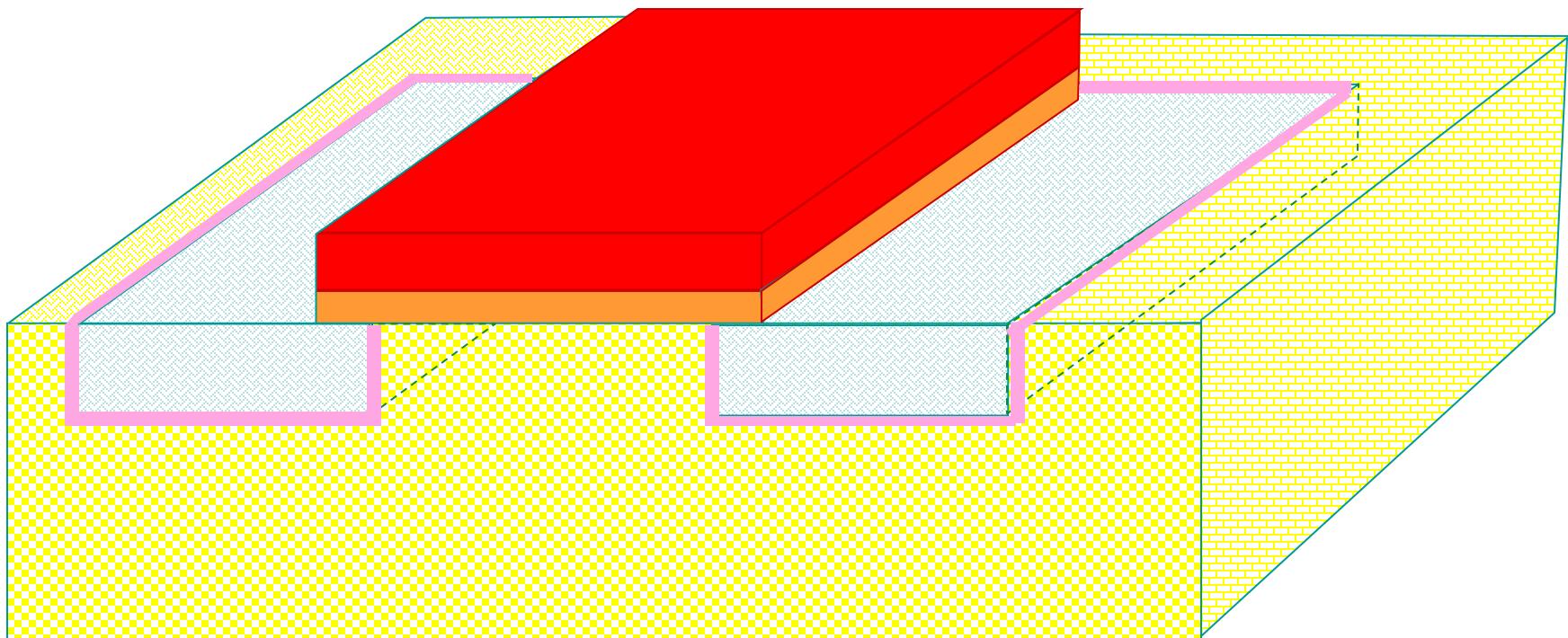


p-sub

# n-Channel MOSFET



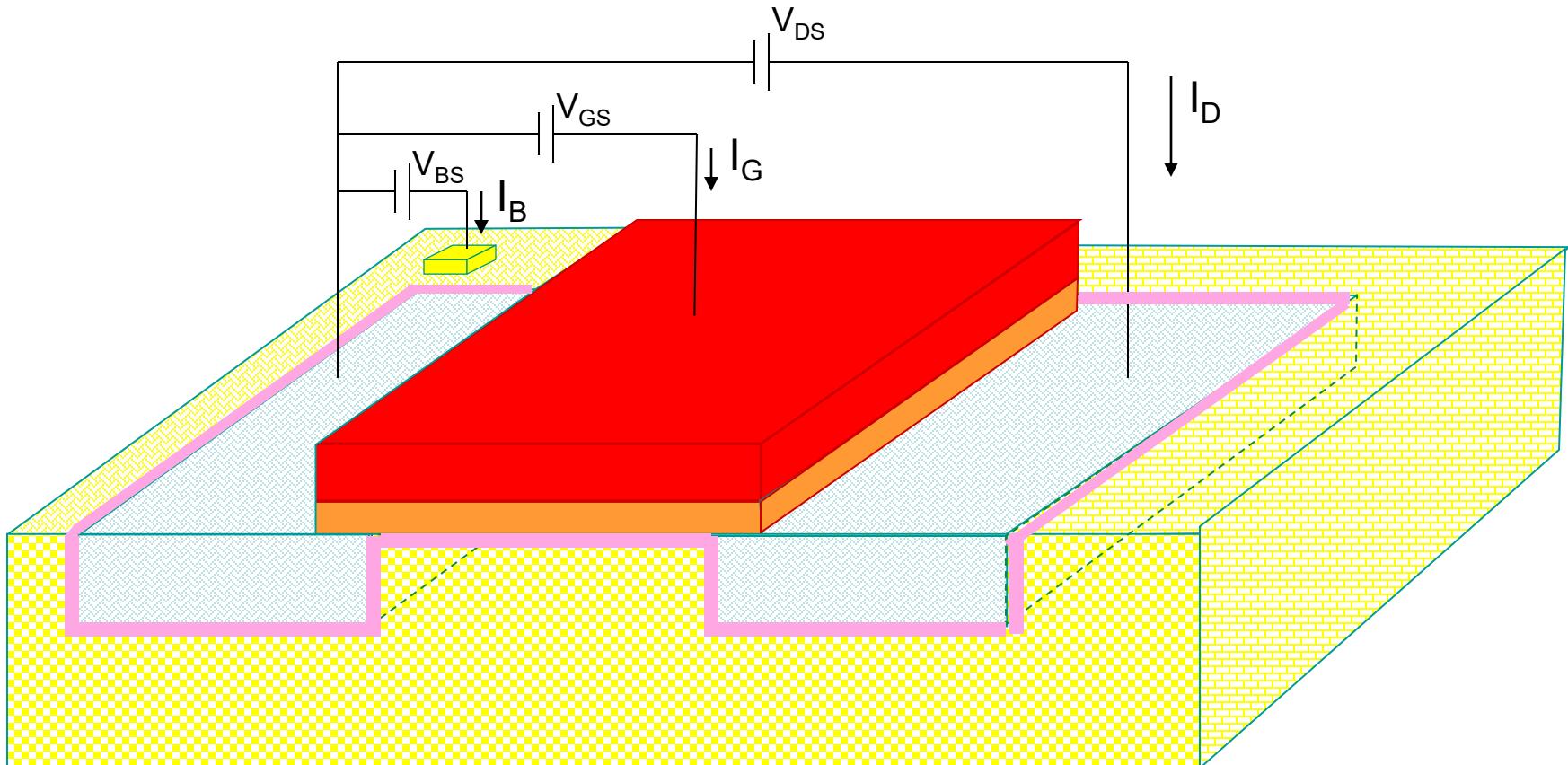
# n-Channel MOSFET



	Poly		Gate oxide
	n-active		p-sub
depletion region (electrically induced)			

- In what follows assume all pn junctions reverse biased (almost always used this way)
- Extremely small reverse bias pn junction current can be neglected in most applications

# n-Channel MOSFET Operation and Model

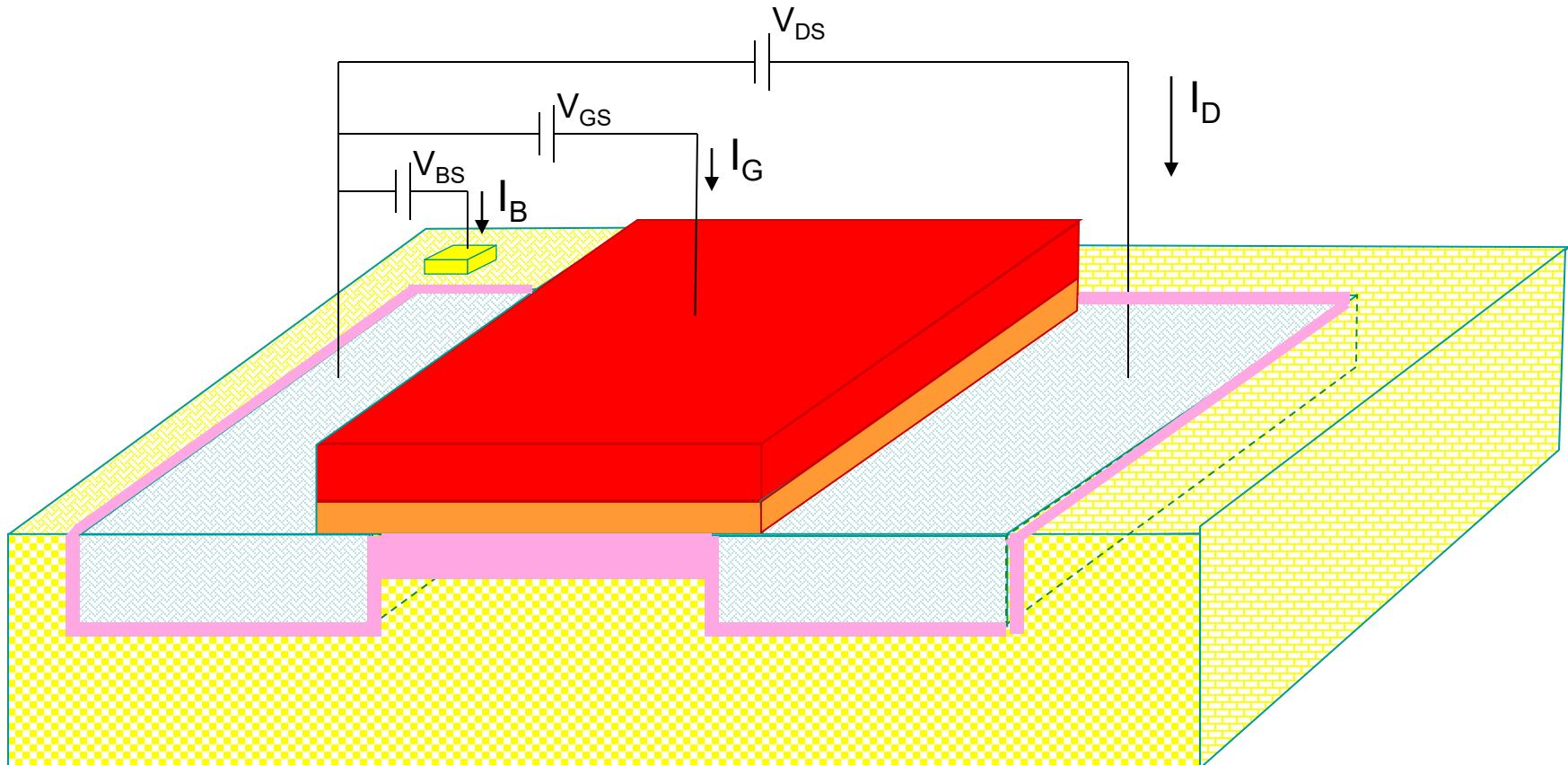


Apply small  $V_{GS}$   
( $V_{DS}$  and  $V_{BS}$  assumed to be small)

Depletion region electrically induced in channel  
Termed “cutoff” region of operation

$$\begin{aligned}I_D &= 0 \\I_G &= 0 \\I_B &= 0\end{aligned}$$

# n-Channel MOSFET Operation and Model

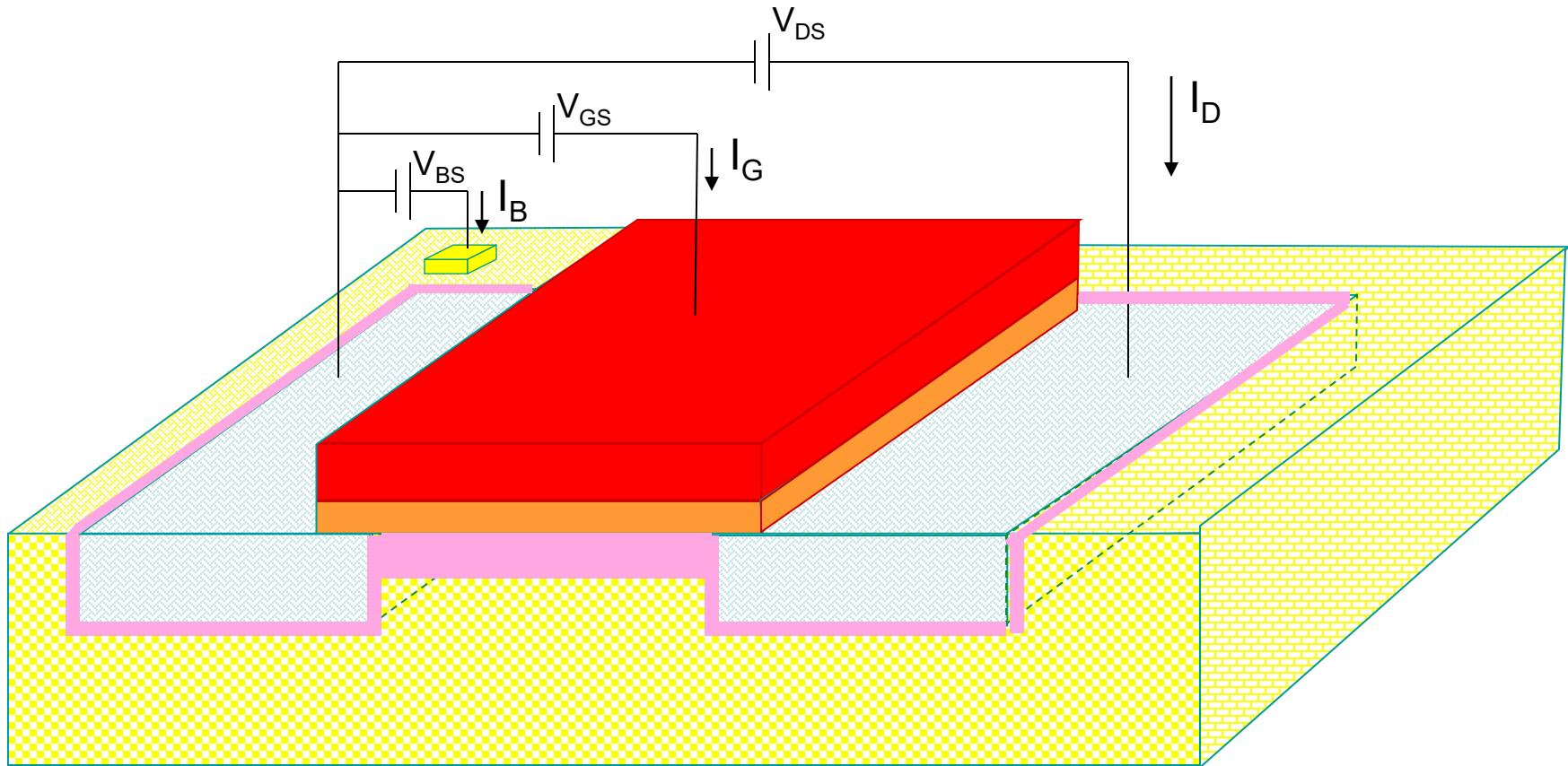


Increase  $V_{GS}$   
( $V_{DS}$  and  $V_{BS}$  assumed to be small)

Depletion region in channel becomes larger

$$\begin{aligned}I_D &= 0 \\I_G &= 0 \\I_B &= 0\end{aligned}$$

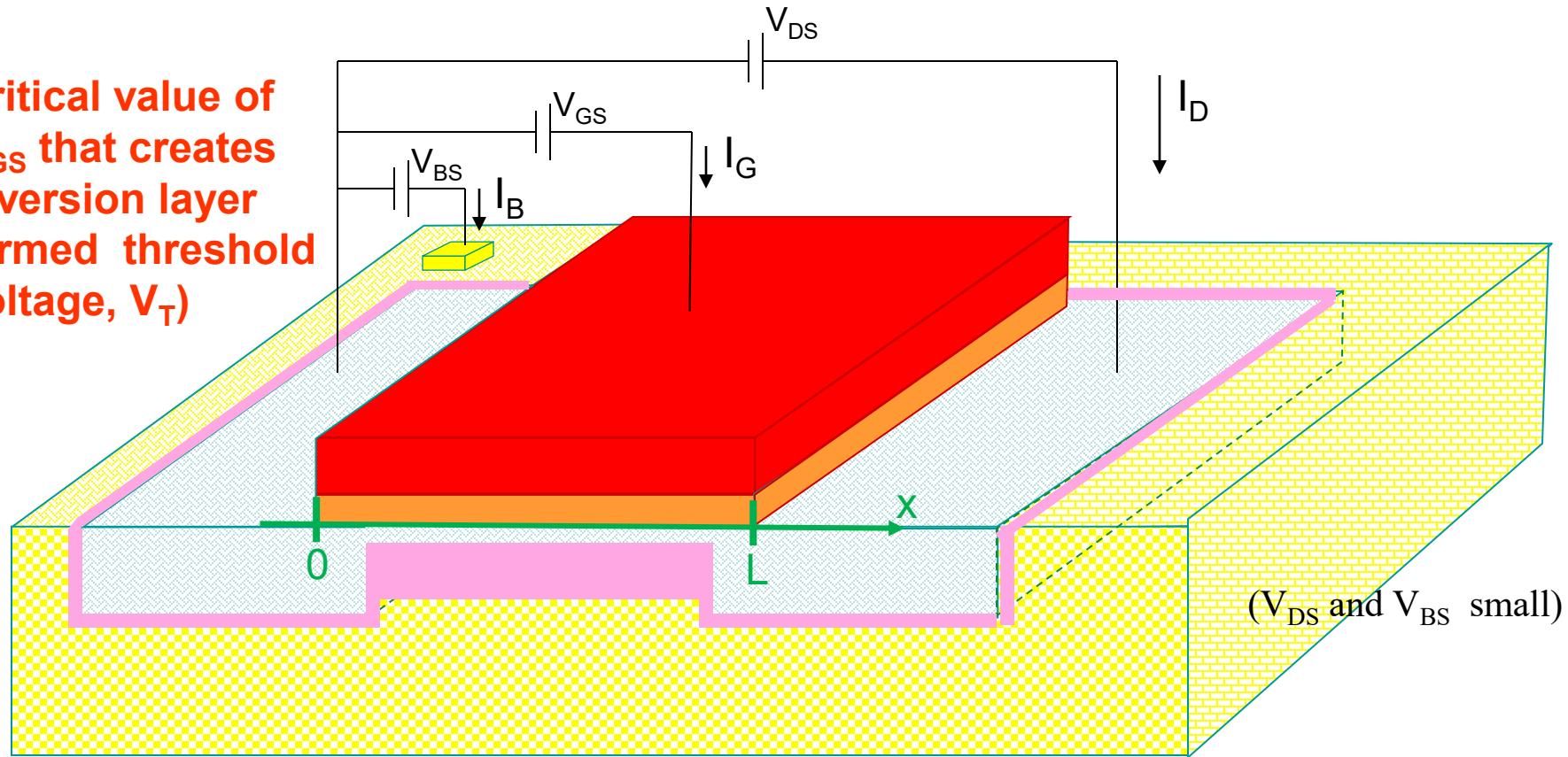
# n-Channel MOSFET Operation and Model



$$\boxed{\begin{aligned} I_D &= 0 \\ I_G &= 0 \\ I_B &= 0 \end{aligned}}$$

Model in Cutoff Region

# n-Channel MOSFET Operation and Model



Increase  $V_{GS}$  more

Inversion layer forms in channel

Inversion layer will support current flow from D to S

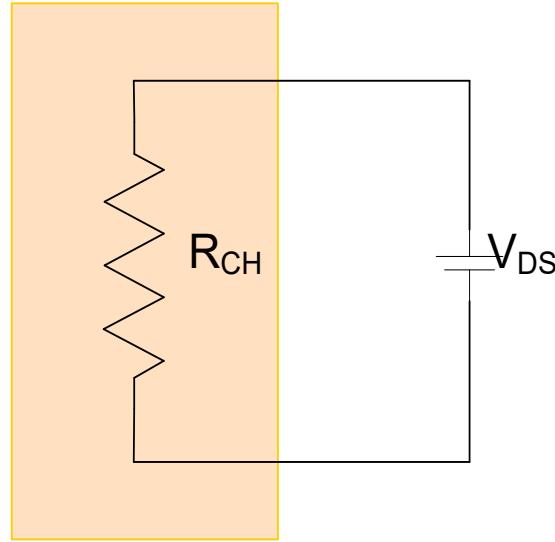
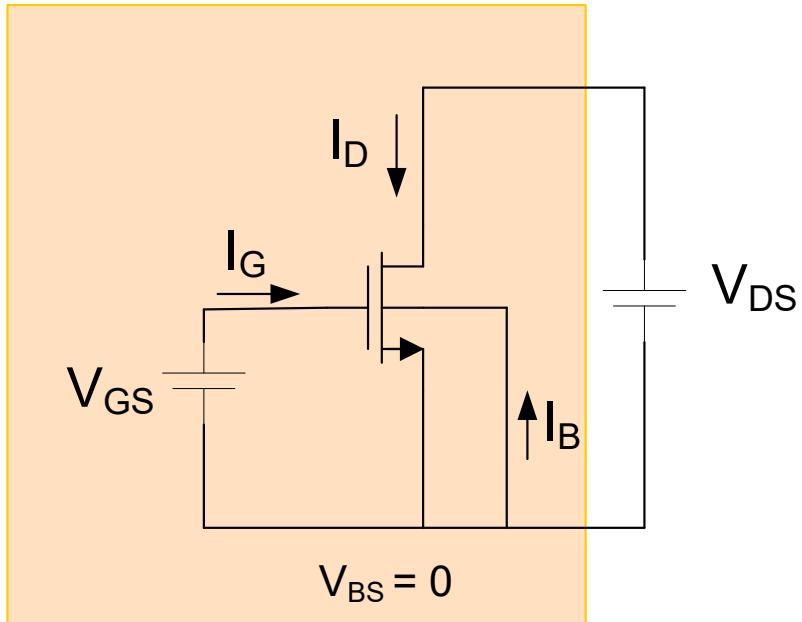
Channel behaves as thin-film resistor

$$I_D R_{CH} = V_{DS}$$

$$I_G = 0$$

$$I_B = 0$$

# Triode Region of Operation



For  $V_{DS}$  small

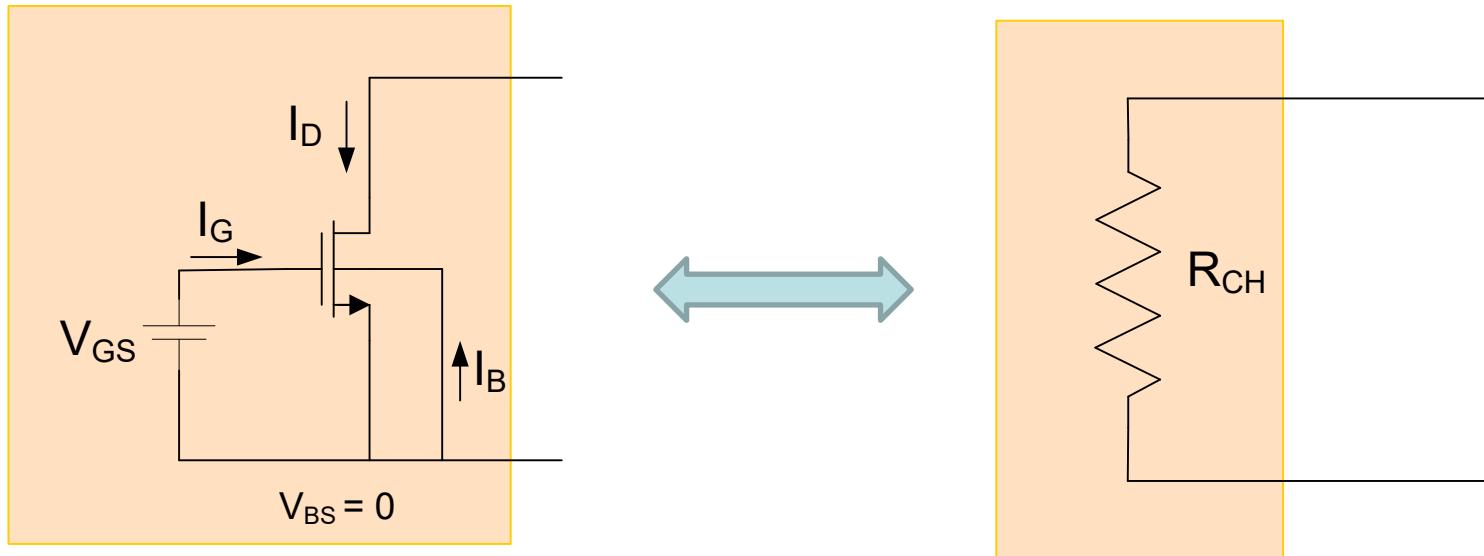
$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{ox}}$$

$$I_D = \mu C_{ox} \frac{W}{L} (V_{GS} - V_{TH}) V_{DS}$$
$$I_G = I_B = 0$$

Behaves as a resistor between drain and source

Model in Deep Triode Region

# Triode Region of Operation

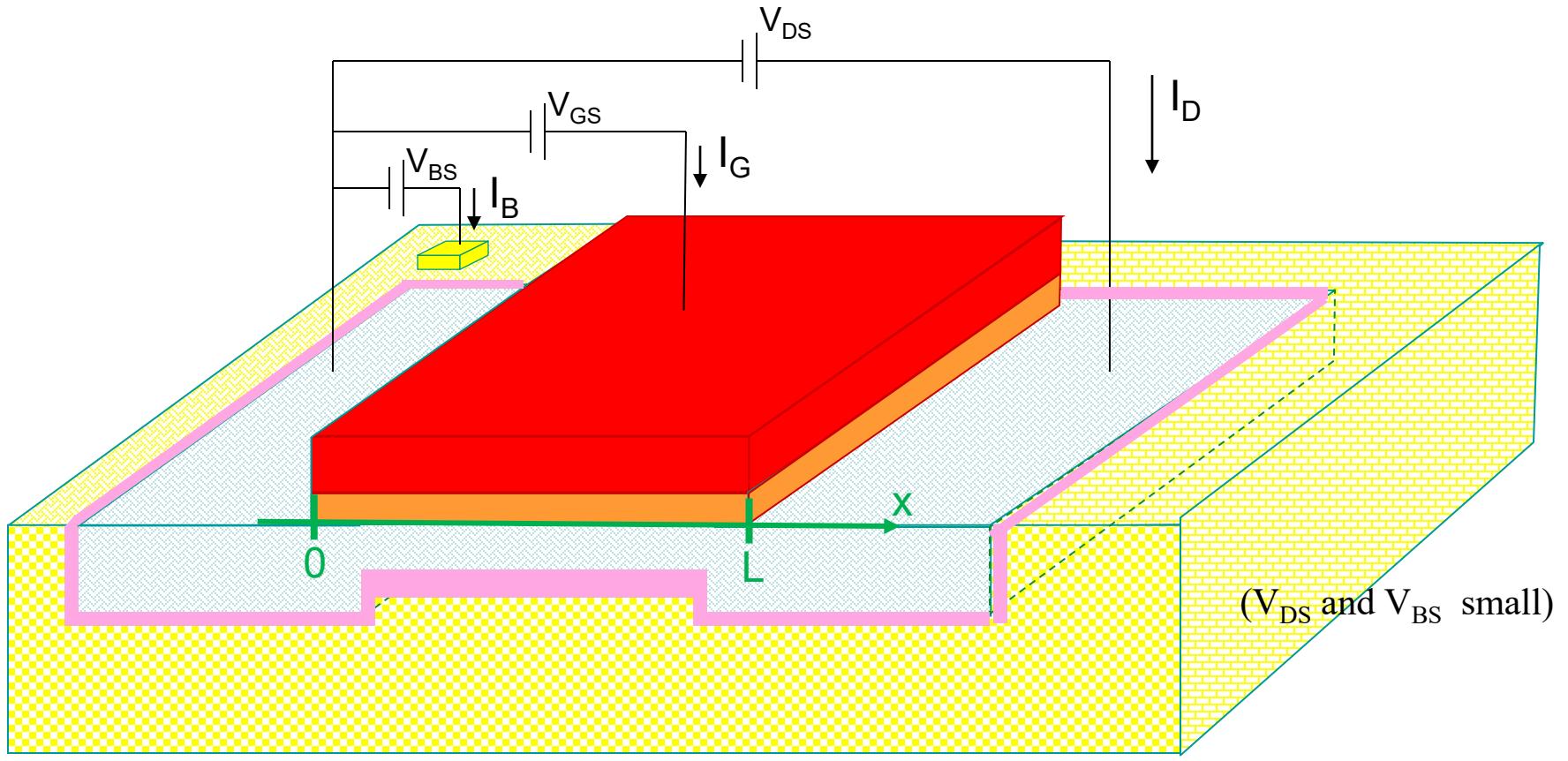


For  $V_{DS}$  small

$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{ox}}$$

Resistor is controlled by the voltage  $V_{GS}$   
Termed a “Voltage Controlled Resistor” (VCR)

# n-Channel MOSFET Operation and Model



Increase  $V_{GS}$  more

Inversion layer in channel thickens

$R_{CH}$  will decrease

Termed “ohmic” or “triode” region of operation

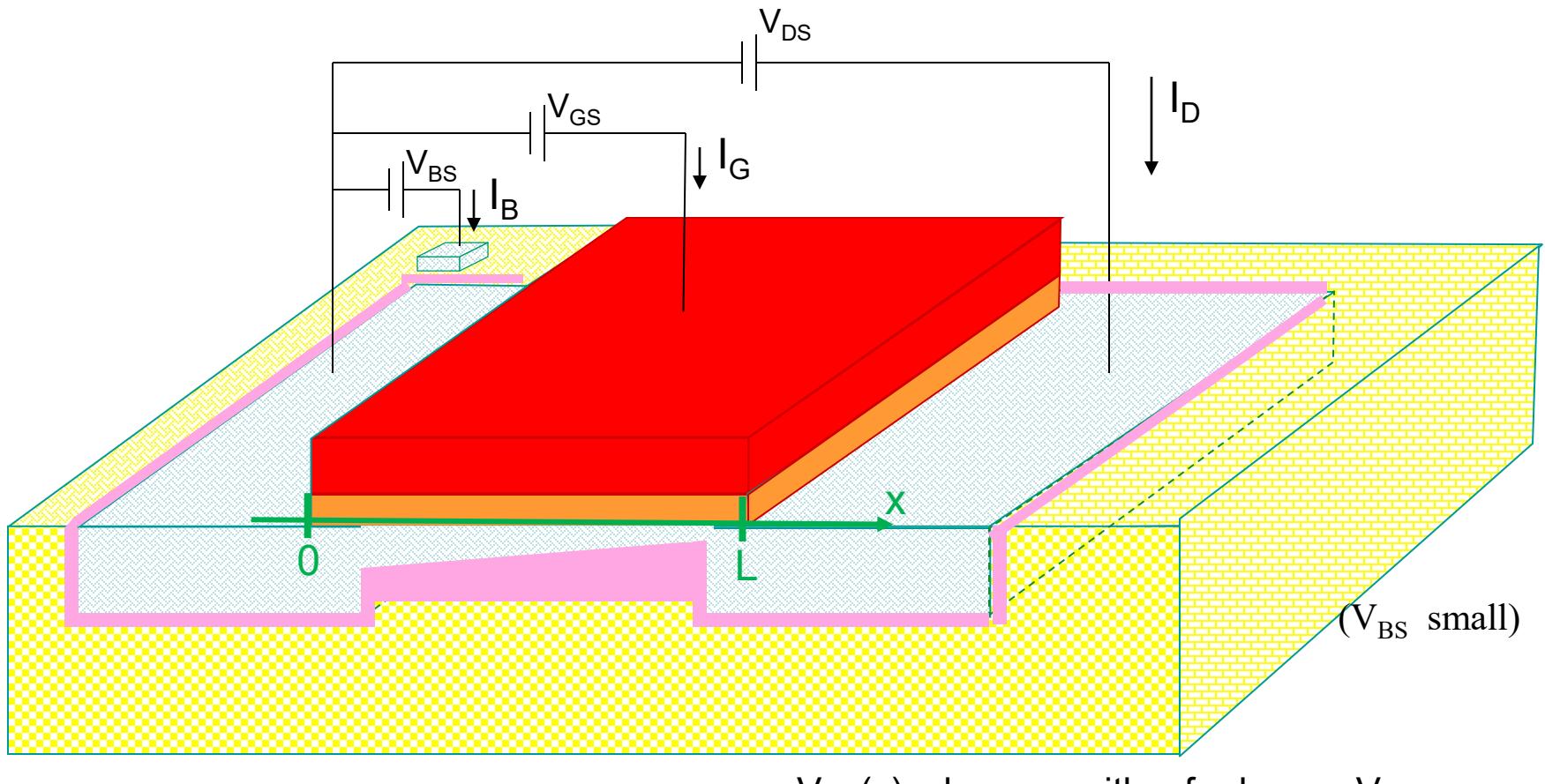
$V_{GC}(x)$  approx. constant for small  $V_{DS}$

$$I_D R_{CH} = V_{DS}$$

$$I_G = 0$$

$$I_B = 0$$

# n-Channel MOSFET Operation and Model



## Increase $V_{DS}$

$V_{GC}(x)$  changes with  $x$  for larger  $V_{DS}$

Inversion layer thins near drain

$I_D$  no longer linearly dependent upon  $V_{DS}$

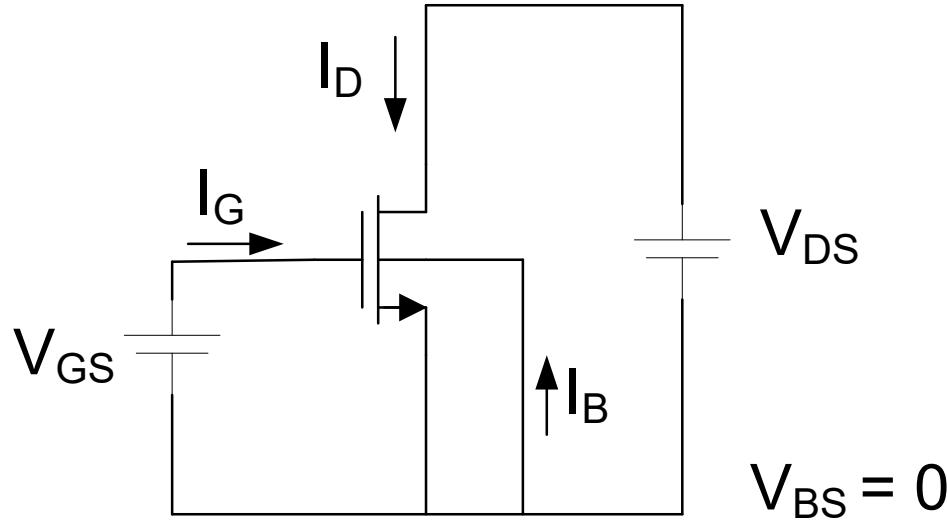
Still termed “ohmic” or “triode” region of operation

$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

# Triode Region of Operation



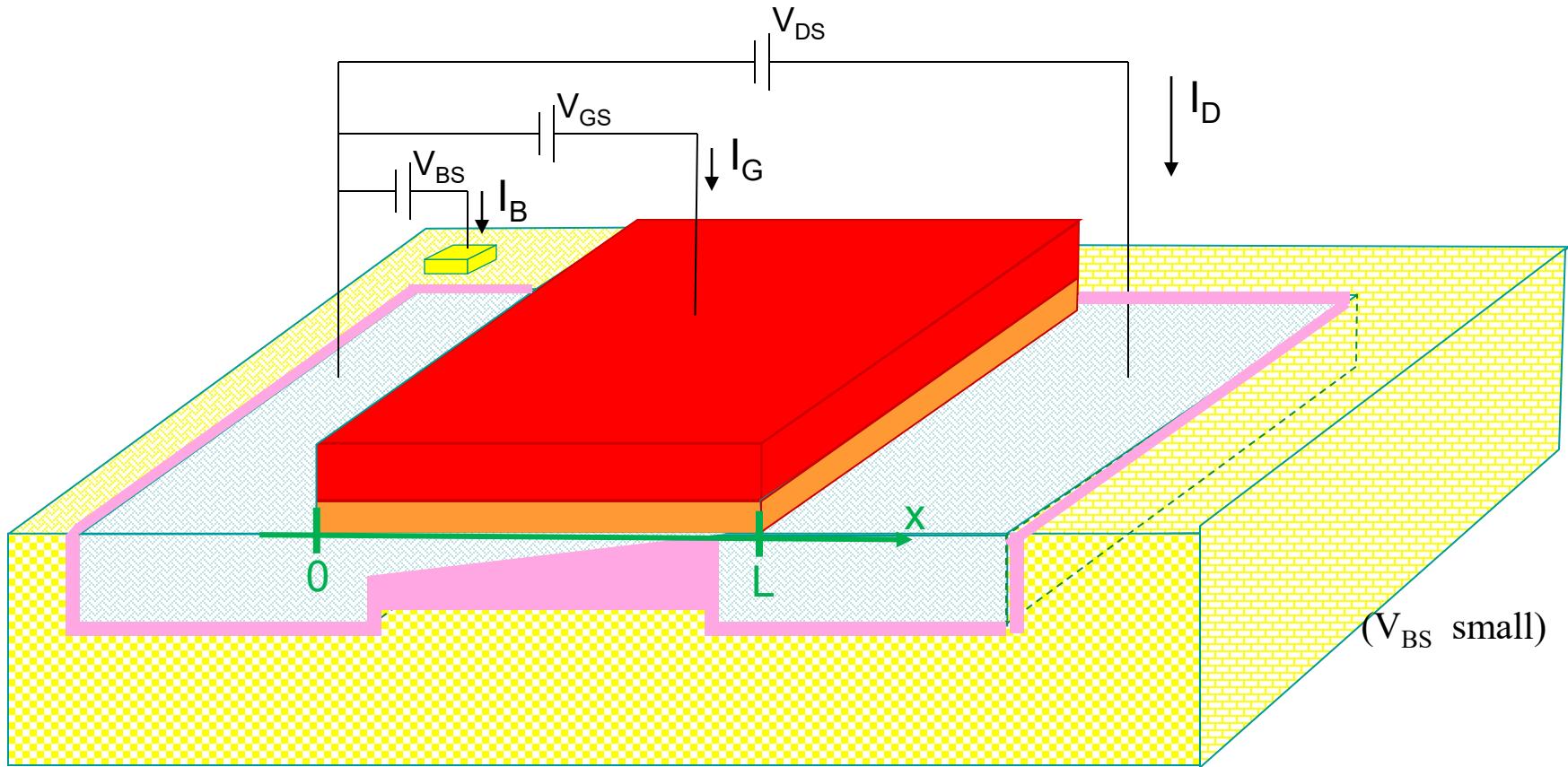
For  $V_{DS}$  larger

$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{ox}}$$

$$I_D = \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$
$$I_G = I_B = 0$$

Model in Triode Region

# n-Channel MOSFET Operation and Model



Increase  $V_{DS}$  even more

$V_{GC}(L) = V_{TH}$  when channel saturates

Inversion layer disappears near drain

$$I_D = ?$$

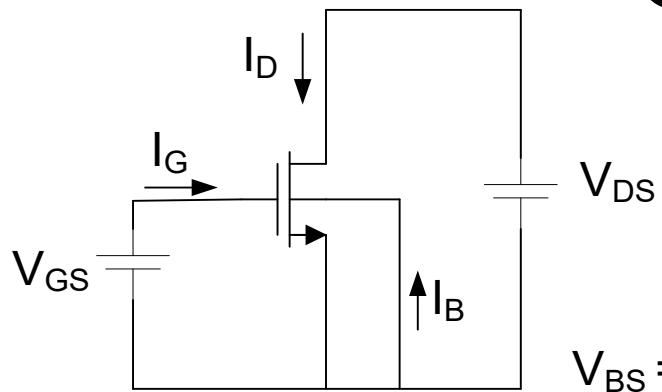
Termed "saturation" region of operation

$$I_G = 0$$

Saturation first occurs when  $V_{DS} = V_{GS} - V_{TH}$

$$I_B = 0$$

# Saturation Region of Operation



For  $V_{DS}$  at onset of saturation

$$I_D = \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$

*or equivalently*

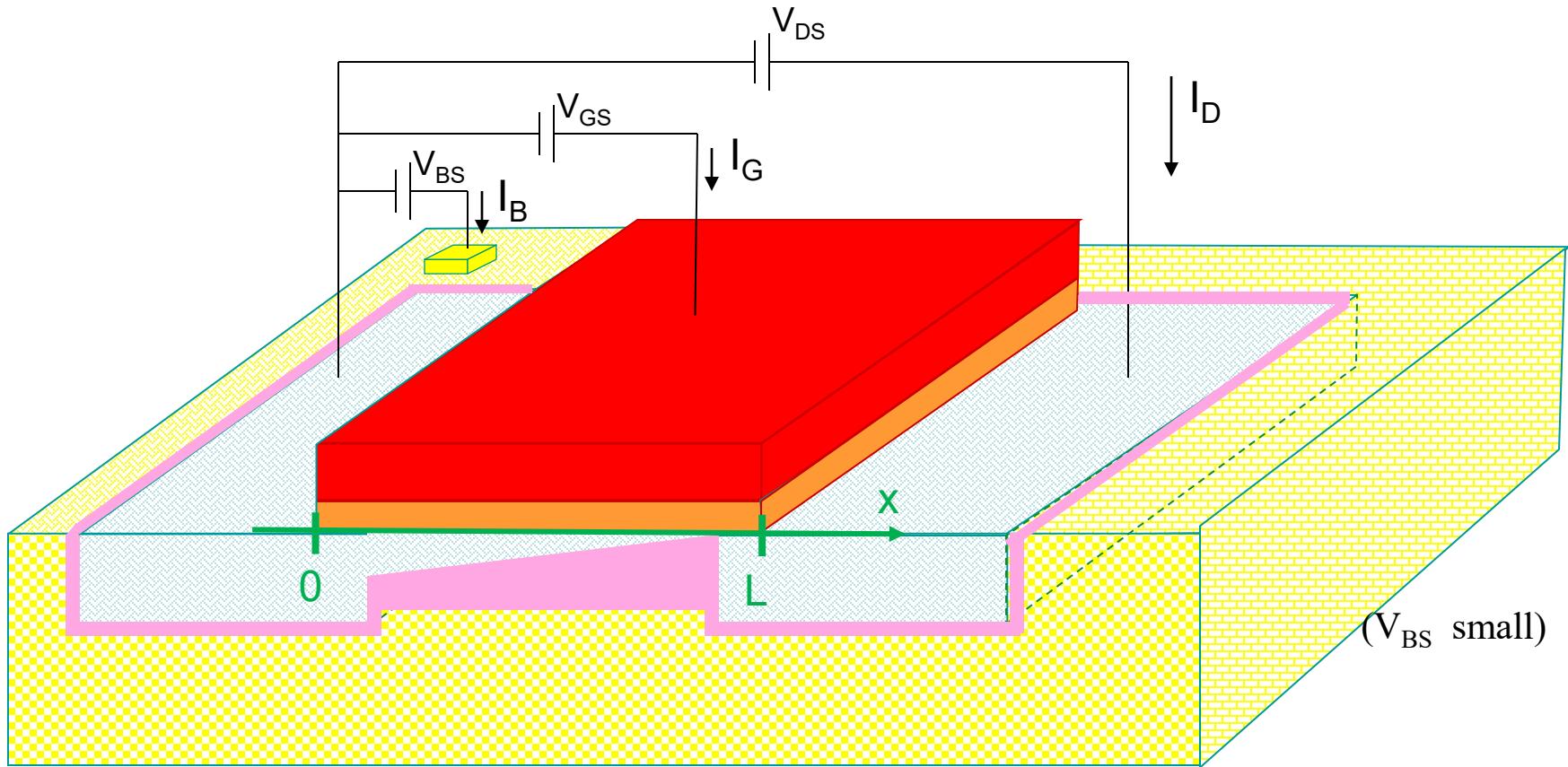
$$I_D = \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{GS} - V_{TH}}{2} \right) (V_{GS} - V_{TH})$$

*or equivalently*

$$I_D = \frac{\mu C_{ox} W}{2L} (V_{GS} - V_{TH})^2$$

$$I_G = I_B = 0$$

# n-Channel MOSFET Operation and Model



Increase  $V_{DS}$  even more (beyond  $V_{GS} - V_{TH}$ )

Nothing much changes !!

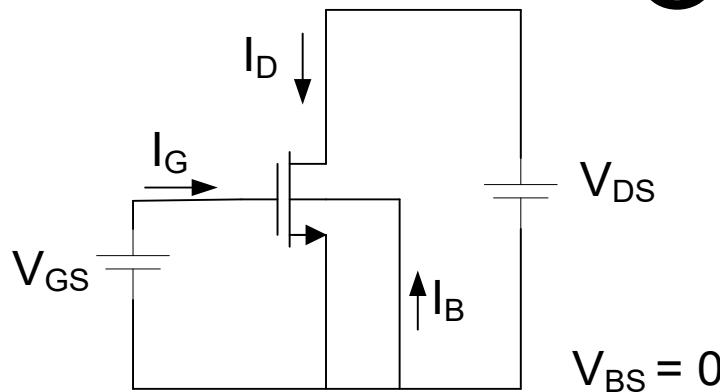
Termed “saturation” region of operation

$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

# Saturation Region of Operation



For  $V_{DS}$  in Saturation

$$I_D = \frac{\mu C_{ox} W}{2L} (V_{GS} - V_{TH})^2$$

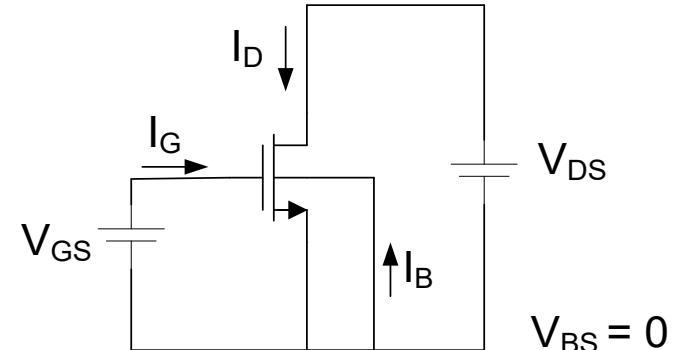
$$I_G = I_B = 0$$

Model in Saturation Region

# Model Summary

# n-channel MOSFET

Notation change:  $V_T = V_{TH}$ , don't confuse  $V_T$  with  $V_t = kT/q$



$$I_G = I_B = 0$$

Model Parameters:  $\{\mu, V_T, C_{ox}\}$  Design Parameters :  $\{W, L\}$

This is a piecewise model (not piecewise linear though)

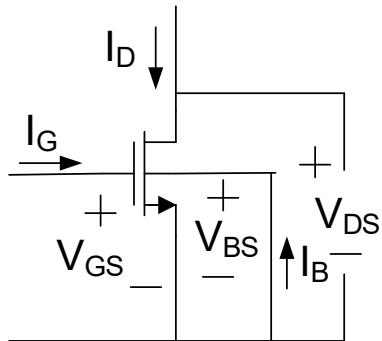
Piecewise model is continuous at transition between regions

(Deep triode special case of triode where  $V_{DS}$  is small     $R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_T)\mu C_{ox}}$  )

Note: This is the third model we have introduced for the MOSFET

# Model Summary

n-channel MOSFET



$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$I_G = I_B = 0$$

Observations about this model (developed for  $V_{BS}=0$ ):

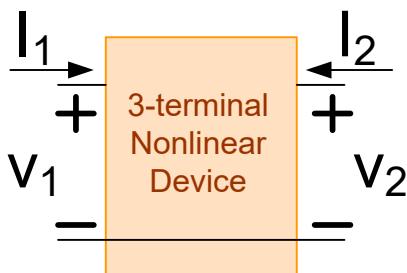
$$I_D = f_1(V_{GS}, V_{DS})$$

$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

This is a nonlinear piecewise model characterized by the functions  $f_1$ ,  $f_2$ , and  $f_3$  where we have assumed that the port voltages  $V_{GS}$  and  $V_{DS}$  are the independent variables and the drain currents are the dependent variables

# General Nonlinear Models

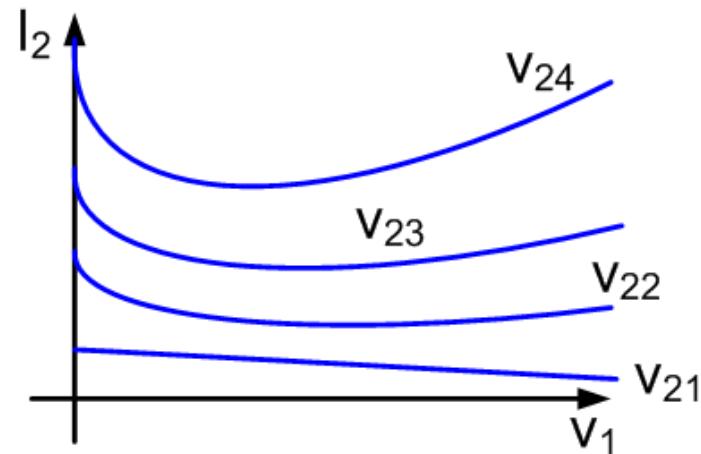
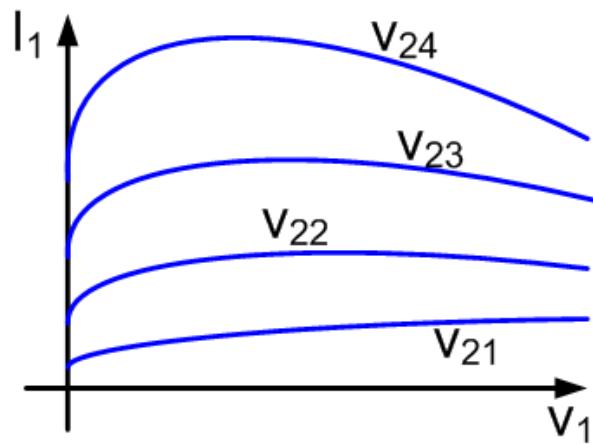


$$I_1 = f_1(V_1, V_2)$$

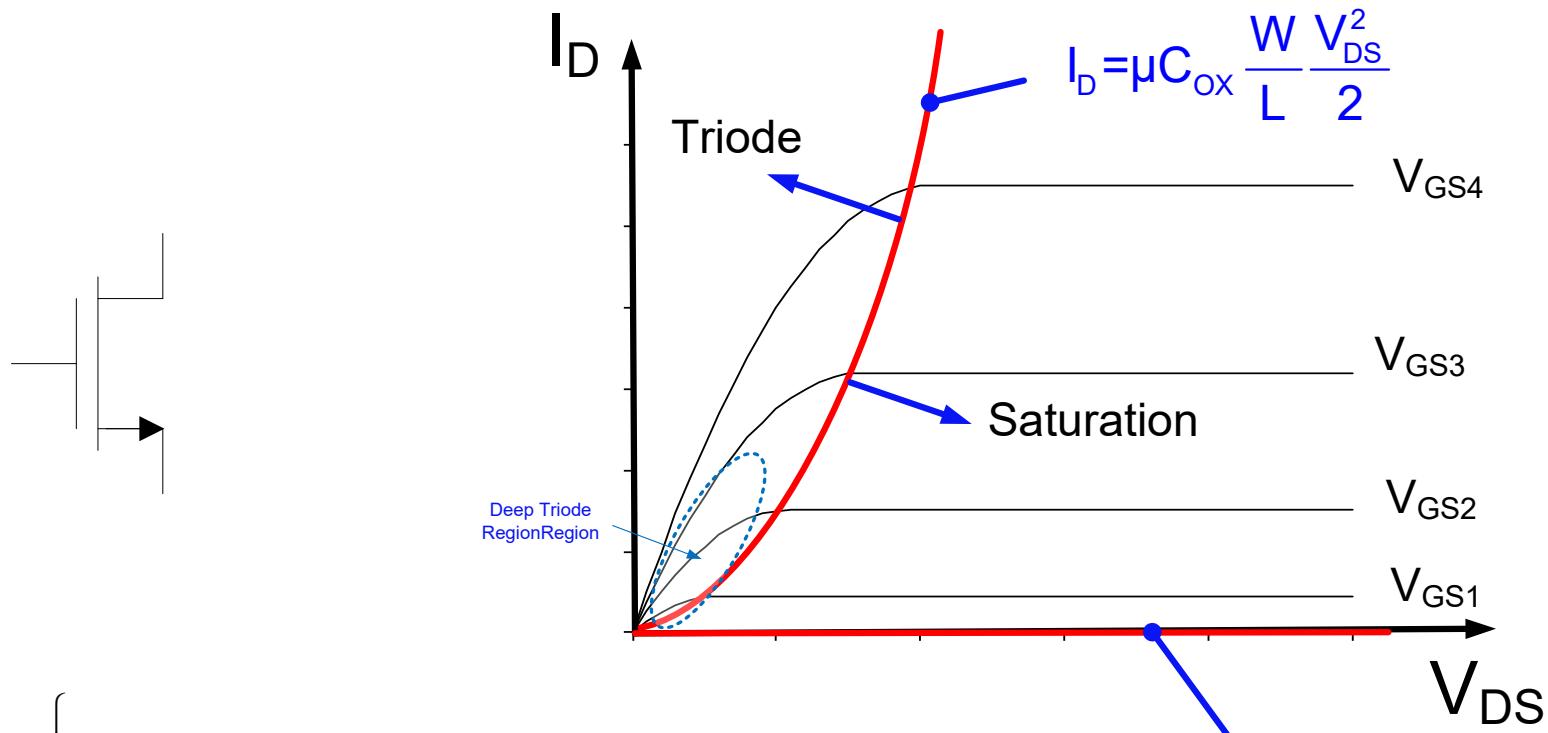
$$I_2 = f_2(V_1, V_2)$$

$I_1$  and  $I_2$  are 3-dimensional relationships which are often difficult to visualize

Two-dimensional representation of 3-dimensional relationships



# Graphical Representation of MOS Model

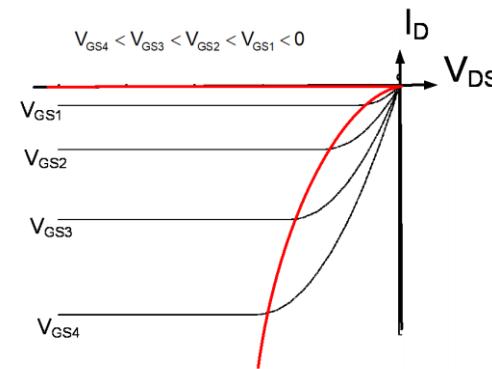
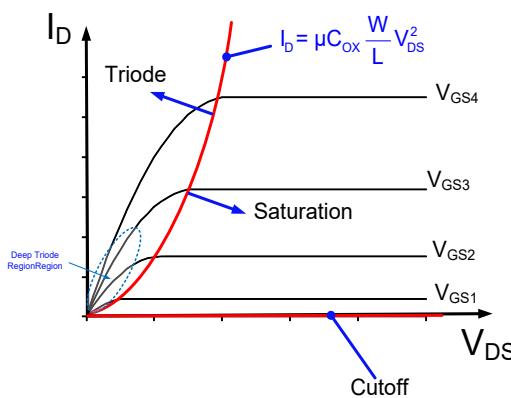
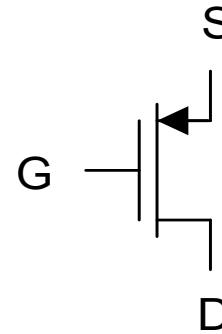
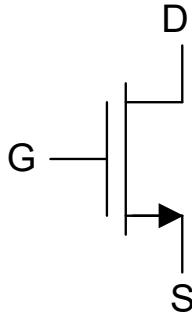


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$I_G = I_B = 0$$

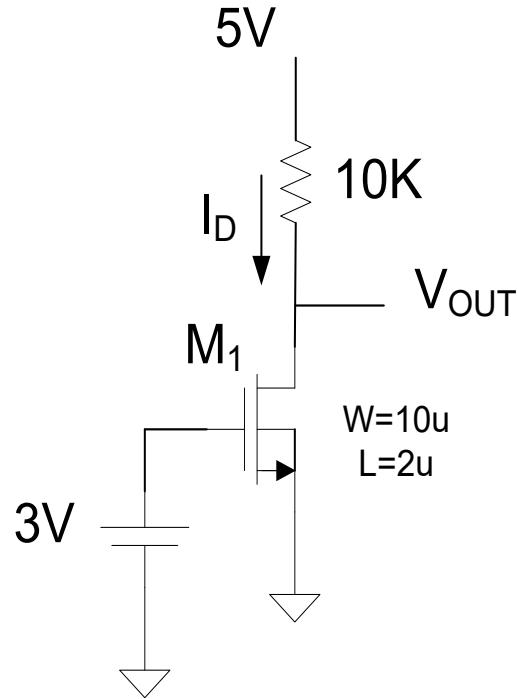
Parabola separated triode and saturation regions and corresponds to  $V_{DS} = V_{GS} - V_T$

# PMOS and NMOS Models



- Functional form identical, sign changes and parameter values different
- Will give details about p-channel model later

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_T=1V$  and  $\mu C_{OX}=100\mu A V^{-2}$

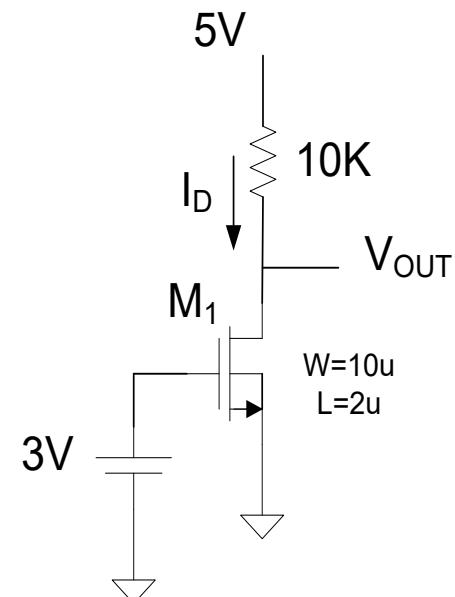


Solution:

Since  $V_{GS} > V_T$ ,  $M_1$  is operating in either saturation or triode region

Strategy will be to guess region of operation, solve, and then verify region

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_T=1V$  and  $\mu C_{Ox}=100\mu A V^{-2}$



Solution:

Guess M<sub>1</sub> in saturation

$$\left. \begin{array}{l} 5V = I_D 10K + V_{OUT} \\ I_D = \frac{\mu C_{Ox} W}{2L} (3 - V_T)^2 \end{array} \right\}$$

Required verification:  $V_{DS} > V_{GS} - V_T$

Can eliminate  $I_D$  between these 2 equations to obtain  $V_{OUT}$

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_T=1V$  and  $\mu C_{OX}=100\mu A V^{-2}$

Guess  $M_1$  in saturation

$$\left. \begin{array}{l} 5V = I_D 10K + V_{OUT} \\ I_D = \frac{\mu C_{OX} W}{2L} (3 - V_T)^2 \end{array} \right\}$$

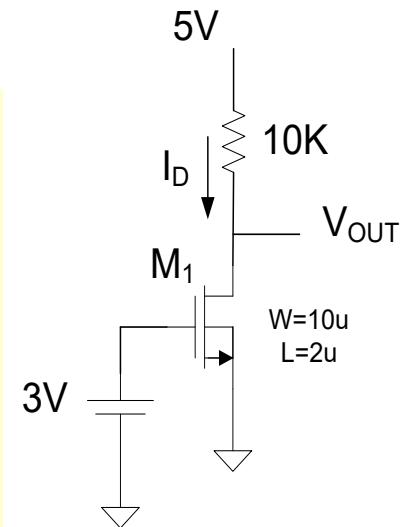
Required verification:  $V_{DS} > V_{GS} - V_T$

$$V_{OUT} = 5V - 10K \left[ \frac{100\mu A V^{-2} 10\mu}{2 \cdot 2\mu} (2V)^2 \right]$$

$$V_{OUT} = -5V$$

Verification:  $V_{DS} = V_{OUT}$

$-5 >? 2V - - 0$  No! So verification fails and Guess of region is invalid



Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_T=1V$  and  $\mu C_{OX}=100\mu A V^{-2}$

Guess  $M_1$  in triode

$$5V = I_D 10K + V_{OUT}$$

$$I_D = \frac{\mu C_{OX} W}{L} \left( 3 - V_T - \frac{V_{DS}}{2} \right) V_{DS} \quad \left. \right\}$$

$$V_{OUT} = 5V - 10K \left[ \frac{100\mu A V^{-2} 10\mu}{2\mu} \left( 2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

$$V_{OUT} = 5V - \left[ 5 \left( 2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

Solving for  $V_{OUT}$ , obtain

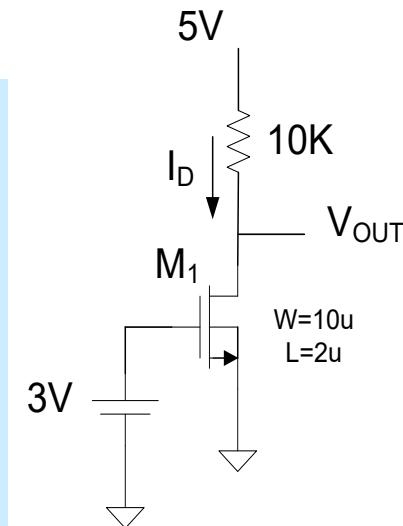
$$V_{OUT} = 0.515V$$

Verification:  $V_{DS} = V_{OUT}$

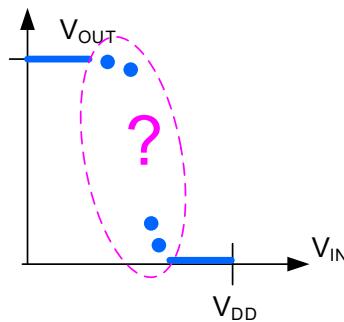
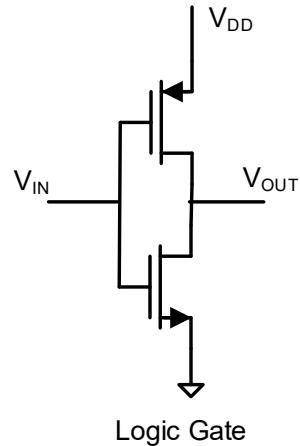
$0.515 <? 2V$  Yes!

So verification succeeds and triode region is valid

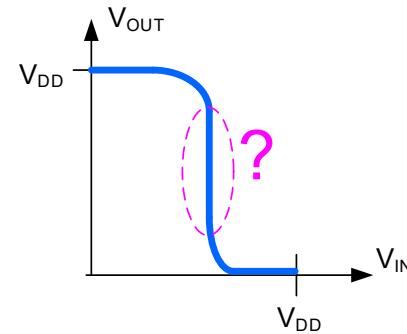
$V_{OUT} = 0.515V$



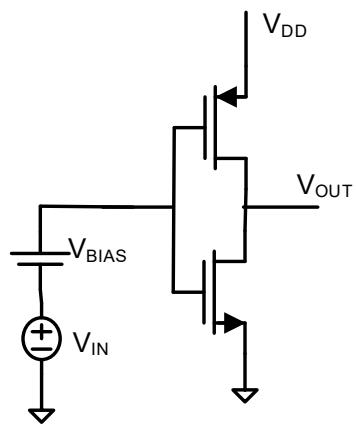
# Limitations of Existing Models



Switch-Level Models



Simple square-law Model



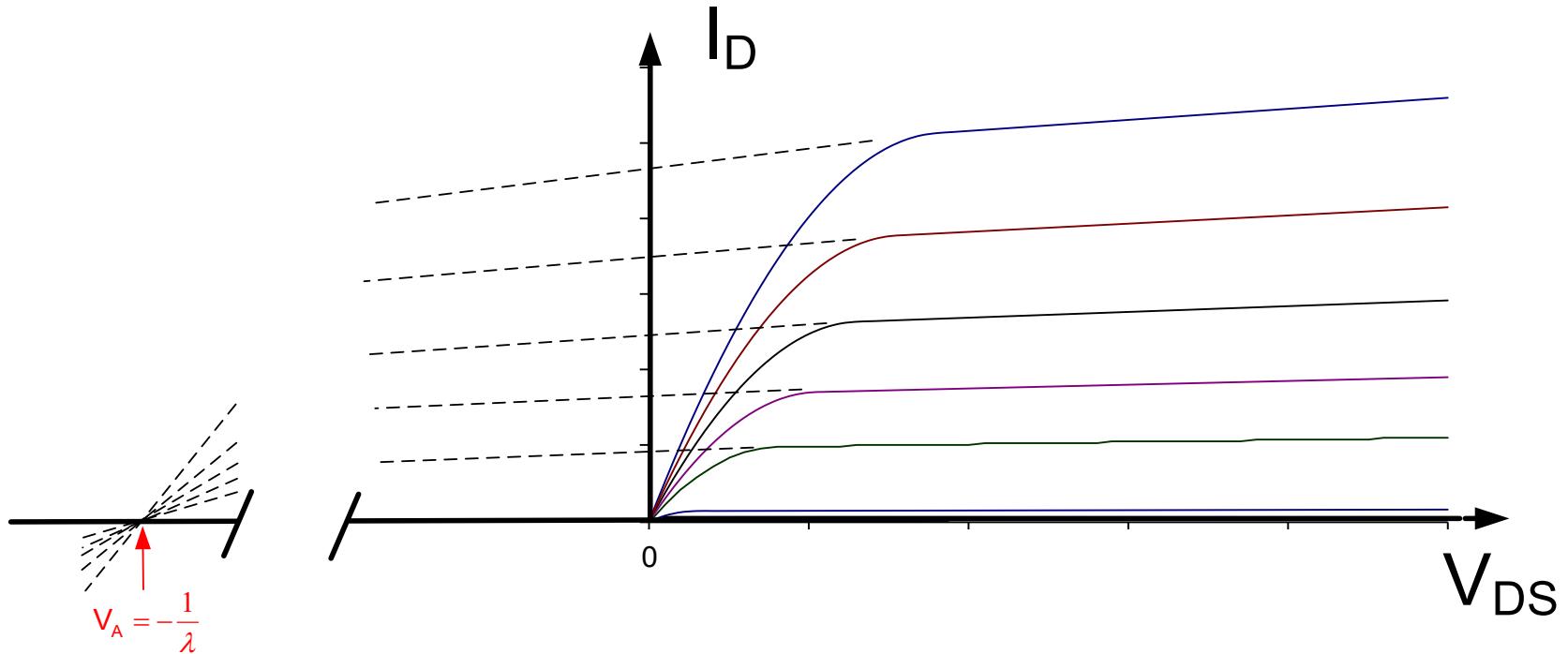
Voltage Amplifier

Switch-Level Models  
Simple square-law Model

Voltage Gain  
Input/Output Relationship

?

# Model Extensions

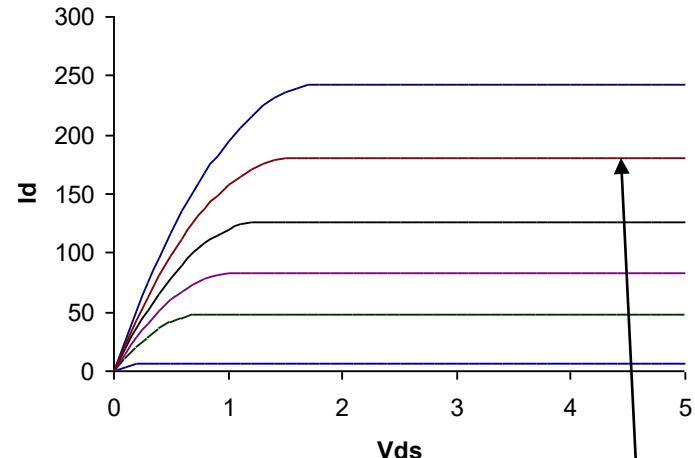


Projections intersect  $-V_{DS}$  axis at same point, termed Early Voltage

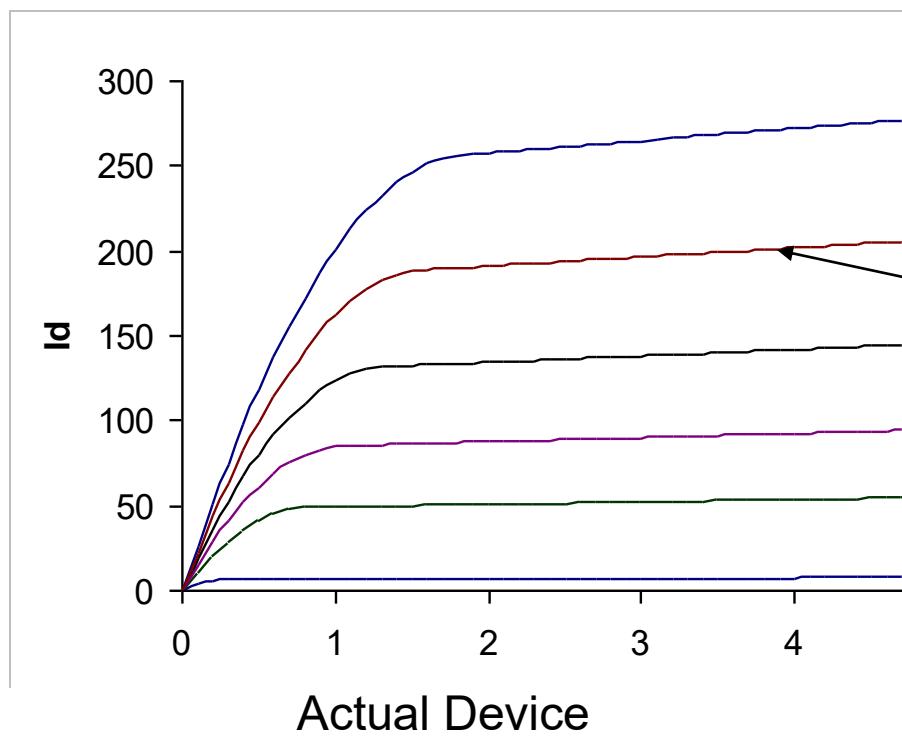
Typical values from -20V to -200V

Usually use parameter  $\lambda$  instead of  $V_A$  in MOS model

# Model Extensions



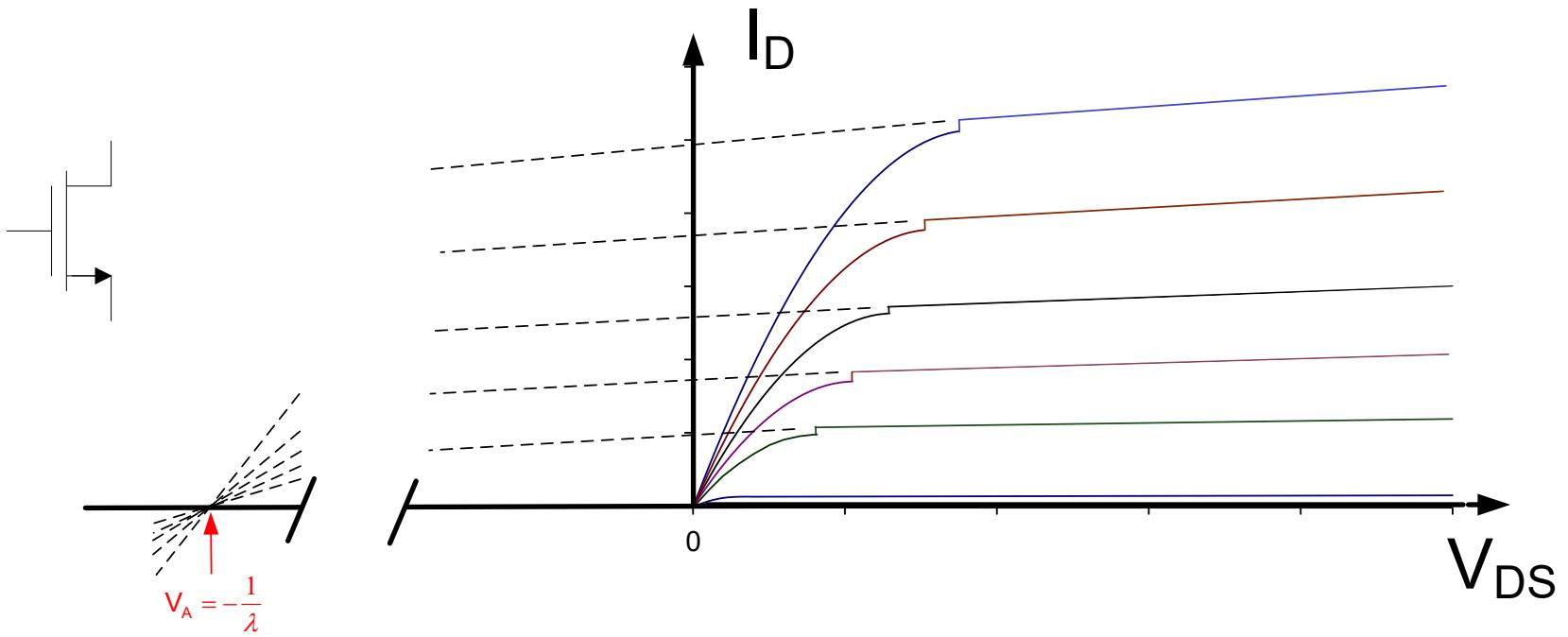
Existing Model



Slope is not 0

Actual Device

# Model Extensions



$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \bullet (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

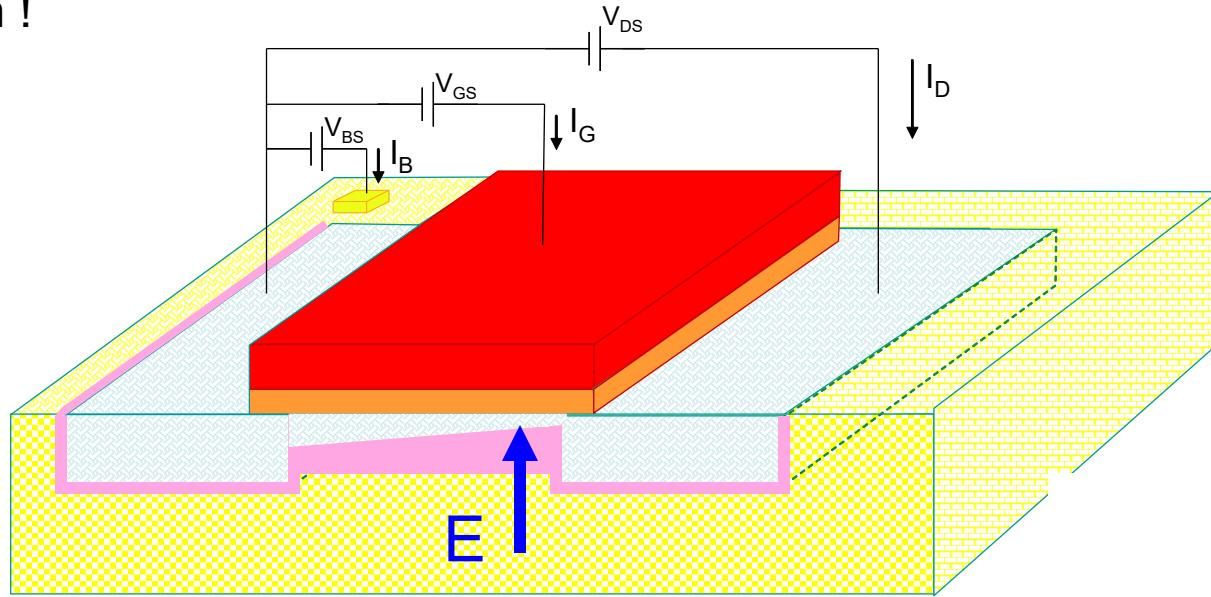
Note: This introduces small discontinuity in model at SAT/Triode transition

# Further Model Extensions

Existing model does not depend upon the bulk voltage !



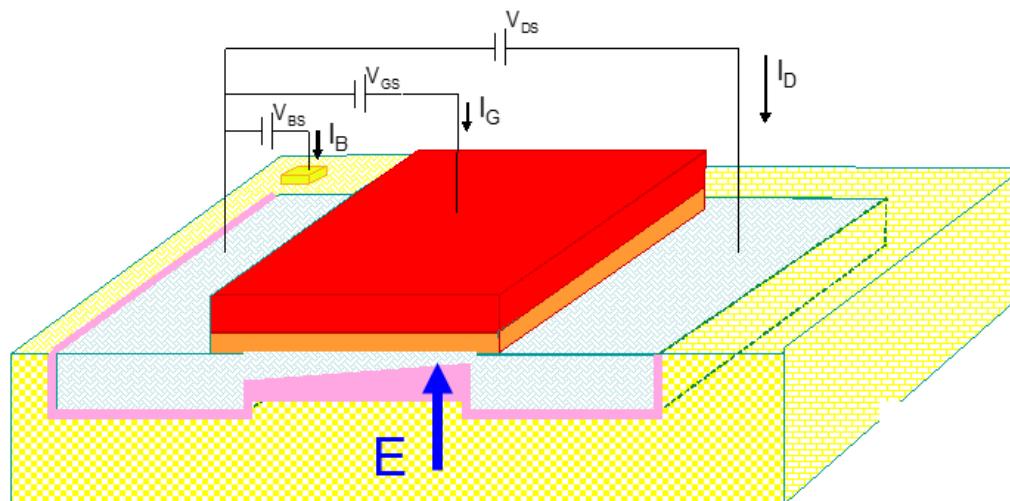
Observe that changing the bulk voltage will change the electric field in the channel region !



# Further Model Extensions

Existing model does not depend upon the bulk voltage !

Observe that changing the bulk voltage will change the electric field in the channel region !



Changing the bulk voltage will change the thickness of the inversion layer

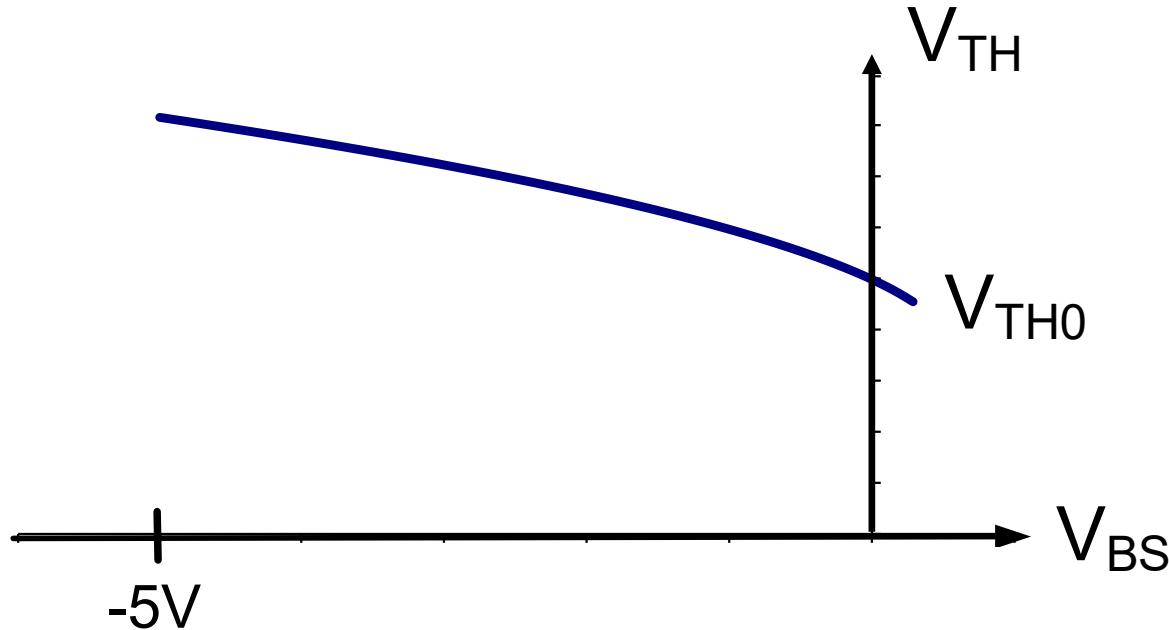
Changing the bulk voltage will change the threshold voltage of the device

$$V_T = V_{T0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

## Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \approx 0.4V^{1/2} \quad \phi \approx 0.6V$$

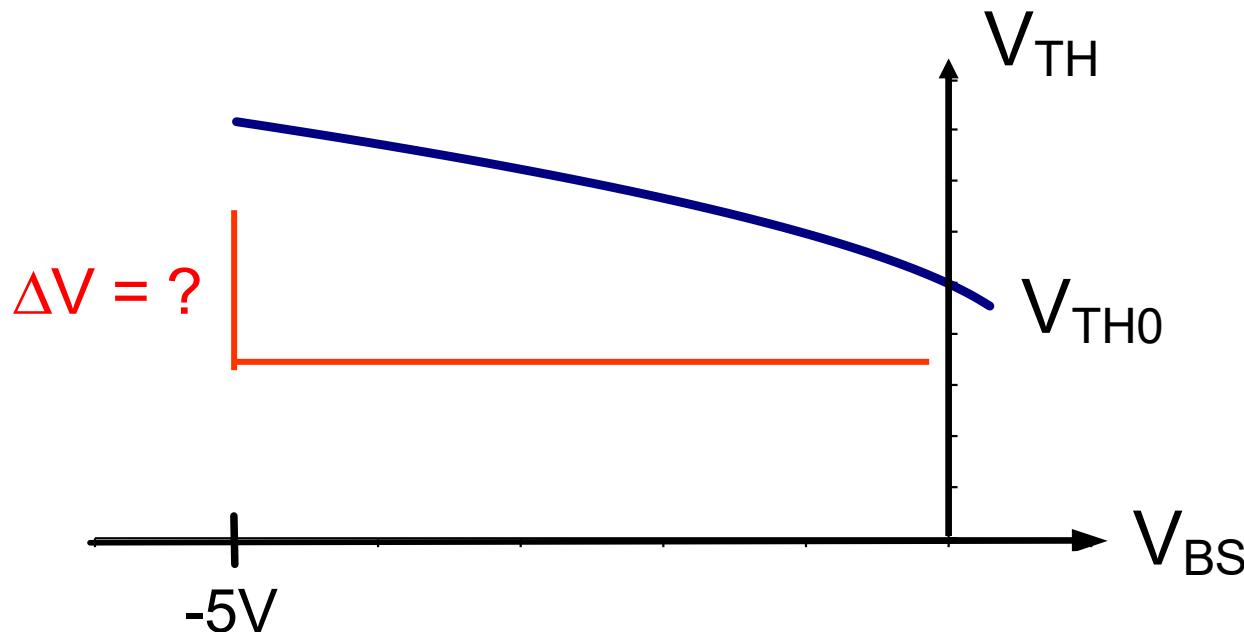


- Bulk-Diffusion Generally Reverse Biased ( $V_{BS} < 0$  or at least  $V_{BS} < 0.3V$ ) for n-channel
- Shift in threshold voltage with bulk voltage can be substantial
- Often  $V_{BS}=0$

## Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \approx 0.4V^{1/2} \quad \phi \approx 0.6V$$



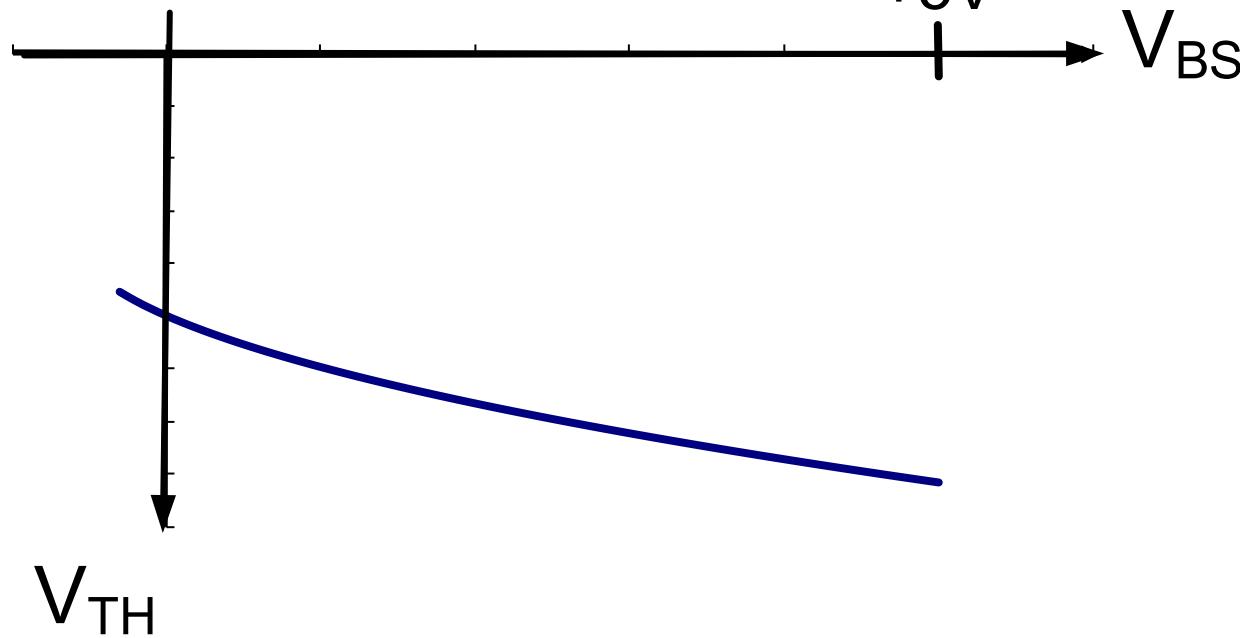
$$\Delta V = V_{TH} - V_{TH0} = \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\Delta V \approx 0.4 \left( \sqrt{0.6V - 5V} - \sqrt{0.6} \right) \approx 0.64V$$

## Typical Bulk Effects on Threshold Voltage for p-channel Devices

$$V_{TH} = V_{TH0} - \gamma \left( \sqrt{\phi + V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \approx 0.4V^{1/2} \quad \phi \approx 0.6V$$

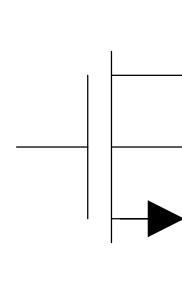


- Bulk-Diffusion Generally Reverse Biased ( $V_{BS} > 0$  or at least  $V_{BS} > -0.3V$ ) for p-channel
- Same functional form as for n-channel but  $V_{TH0} < 0$
- Magnitude of threshold voltage increases with magnitude of reverse bias

# Model Extension Summary

$$I_G = 0$$

$$I_B = 0$$

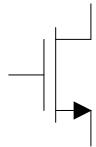


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \bullet (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

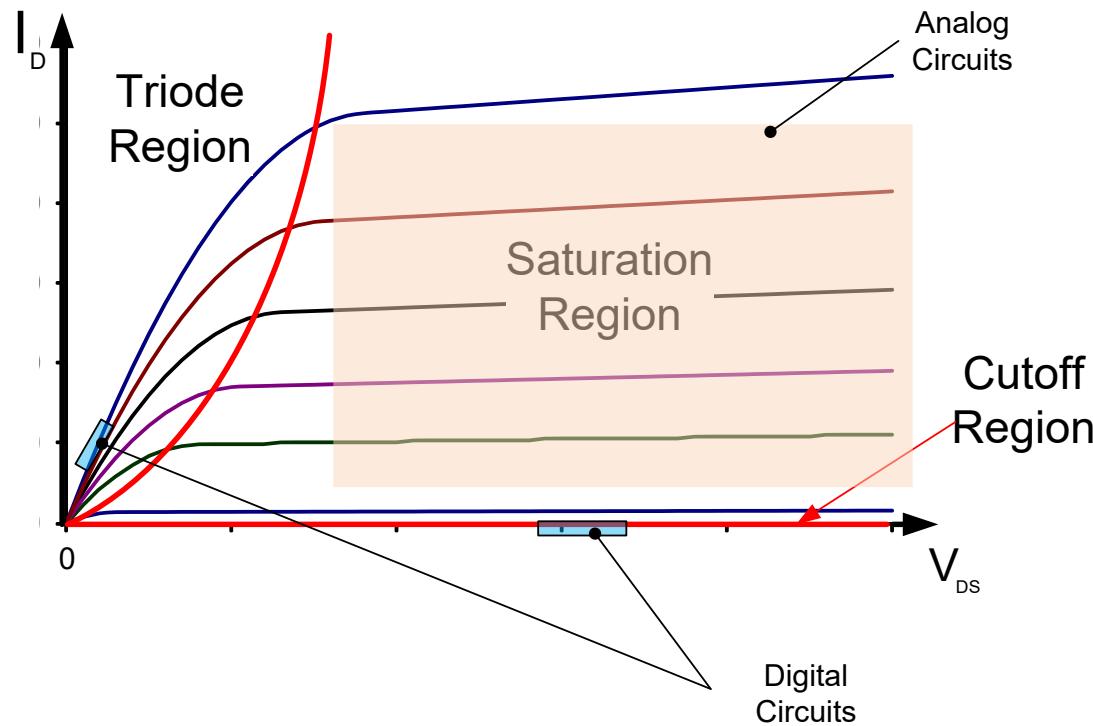
$$V_T = V_{T0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

Model Parameters :  $\{\mu, C_{ox}, V_{T0}, \phi, \gamma, \lambda\}$

Design Parameters :  $\{W, L\}$  but only one degree of freedom W/L



# Operation Regions by Applications



Most analog circuits operate in the saturation region

(basic VVR operates in triode and is an exception)

Most digital circuits operate in triode and cutoff regions and switch between these two with Boolean inputs

# Model Extension (short devices)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

As the channel length becomes very short, velocity saturation will occur in the channel and this will occur with electric fields around  $2V/u$ . So, if a gate length is around 1u, then voltages up to 2V can be applied without velocity saturation. But, if gate length decreases and voltages are kept high, velocity saturation will occur

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\alpha} & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \end{cases}$$

$\alpha$  is the velocity saturation index,  $2 \geq \alpha \geq 1$

# Model Extension (short devices)

(n-channel device)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\alpha} V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\alpha} & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \end{cases}$$

$\alpha$  is the velocity saturation index,  $2 \geq \alpha \geq 1$

No longer a square-law model (some term it an  $\alpha$ -power or  $\alpha$ -law model)

For long devices,  $\alpha=2$

Channel length modulation ( $\lambda$ ) and bulk effects can be added to the velocity Saturation as well

Degrading of  $\alpha$  is not an attractive limitation of the MOSFET

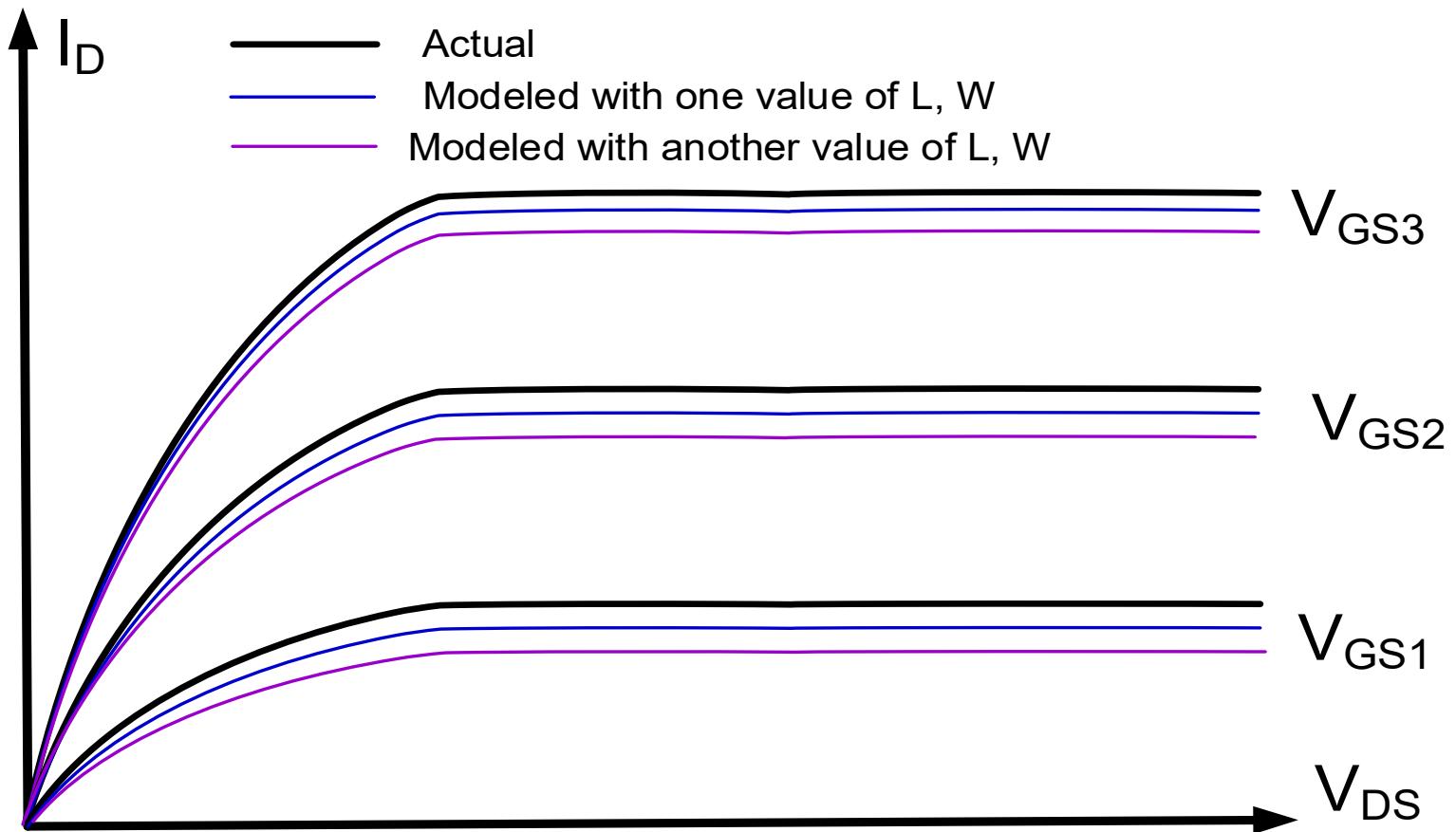
Be aware of existence but of little use !

(too complicated for analytical calculations, not accurate enough for simulations)

# Model Extension (BSIM model)

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27           LEVEL   = 49
+XJ      = 1.5E-7        NCH     = 1.7E17       TOX     = 1.42E-8
+K1      = 0.8976376     K2      = -0.09255     VTH0    = 0.629035
+K3B     = -8.2369696    W0      = 1.041146E-8  K3      = 24.0984767
+DVT0W   = 0             DVT1W   = 0            NLX     = 1E-9
+DVT0    = 2.7123969     DVT1   = 0.4232931    DVT2W   = 0
+U0      = 451.2322004   UA      = 3.091785E-13  DVT2    = -0.1403765
+UC      = 1.22401E-11    VSAT    = 1.715884E5   UB      = 1.702517E-18
+AGS     = 0.130484      B0      = 2.446405E-6  A0      = 0.6580918
+KETA    = -3.043349E-3   A1      = 8.18159E-7   B1      = 5E-6
+RDSW    = 1.367055E3    PRWG    = 0.0328586    A2      = 0.3363058
+WR      = 1              WINT    = 2.443677E-7  PRWB    = 0.0104806
+XL      = 1E-7          XW      = 0            LINT    = 6.999776E-8
+DWB     = 3.676235E-8   VOFF    = -1.493503E-4  DWG     = -1.256454E-8
+CIT     = 0              CDSC    = 2.4E-4        NFACTOR = 1.0354201
+CDSCB   = 0              ETA0    = 2.342963E-3  CDSCD   = 0
+DSUB    = 0.0764123     PCLM    = 2.5941582    ETAB    = -1.5324E-4
+PDIBLC2 = 2.366707E-3  PDIBLCB = -0.0431505  PDIBLC1 = 0.8187825
+PSCBE1  = 6.611774E8   PSCBE2 = 3.238266E-4  DROUT   = 0.9919348
+PRT     = 0              UTE     = -1.5          PVAG    = 0
+KT1L    = 0              KT2     = 0.022        KT1     = -0.11
+UB1     = -7.61E-18      UC1     = -5.6E-11     UA1     = 4.31E-9
+WL      = 0              WLN     = 1            AT      = 3.3E4
+WWN     = 1              WWL     = 0            WW     = 0
+LLN     = 1              LW      = 0            LL      = 0
+LWL     = 0              CAPMOD = 2            LWN     = 1
+CGDO    = 2.32E-10      CGSO    = 2.32E-10     XPART   = 0.5
+CJ      = 4.282017E-4    PB      = 0.9317787   CGBO    = 1E-9
+CJSW    = 3.034055E-10   PBSW    = 0.8          MJ      = 0.4495867
+CJSWG   = 1.64E-10      PBSWG   = 0.8          MJSW    = 0.1713852
+CF      = 0              PVTH0   = 0.0520855   MJSWG   = 0.1713852
+PK2     = -0.0289036    WKETA   = -0.0237483  PRDSW   = 112.8875816
*
*)
```

# Model Errors with Different W/L Values



Binning models can improve model accuracy

# BSIM Binning Model

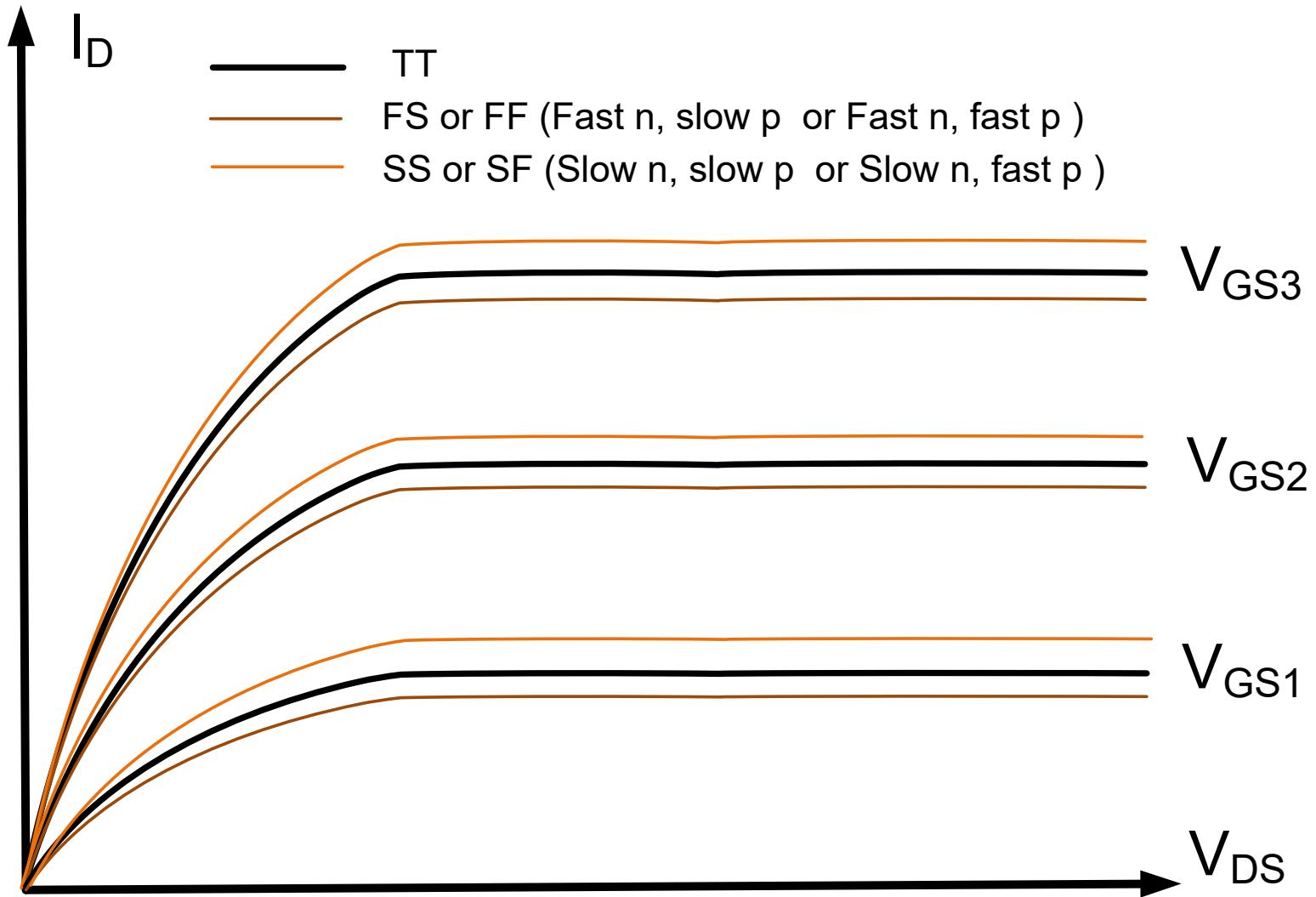
- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVT0W   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN    = 1
+LLN    = 1
+LWL    = 0
+CGDO   = 2.32E-10
+CJ      = 4.282017E-4
+CJSW   = 3.034055E-10
+CJSWG  = 1.64E-10
+CF      = 0
+PK2    = -0.0289036
TNOM     = 27
NCH      = 1.7E17
K2       = -0.09255
W0       = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA       = 3.091785E-13
VSAT    = 1.715884E5
B0       = 2.446405E-6
A1       = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW       = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETA0    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW   = 0.8
PBSWG  = 0.8
PVTH0   = 0.0520855
WKETA  = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0   = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB   = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
KT1     = -0.11
UA1    = 4.31E-9
AT      = 3.3E4
WW     = 0
LL     = 0
LWN    = 1
XPART  = 0.5
CGBO   = 1E-9
MJ      = 0.4495867
MJSW   = 0.1713852
MJSWG  = 0.1713852
PRDSW  = 112.8875816
LKETA  = 1.728324E-3
)
```

\* With 32 bins, this model has 3040 model parameters !

# Model Changes with Process Variations

(n-ch characteristics shown)



Corner models can improve model accuracy

# BSIM Corner Models with Binning

- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS

- bin on device sizes

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVTOW   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+DELTAT  = 0.01
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN     = 1
+LLN     = 1
+LWL     = 0
+CGDO    = 2.32E-10
+CJ      = 4.282017E-4
+CJSW    = 3.034055E-10
+CJSWG   = 1.64E-10
+CF      = 0
+PK2     = -0.0289036
TNOM    = 27
NCH     = 1.7E17
K2      = -0.09255
W0      = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA      = 3.091785E-13
VSAT    = 1.715884E5
B0      = 2.446405E-6
A1      = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW      = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETAO    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
RSH     = 83.5
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW    = 0.8
PBSWG   = 0.8
PVTH0   = 0.0520855
WKETA   = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0    = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB    = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
MORMOD  = 1
KT1     = -0.11
UA1     = 4.31E-9
AT      = 3.3E4
WW     = 0
LL      = 0
LWN    = 1
XPART   = 0.5
CGBO    = 1E-9
MJ      = 0.4495867
MJSW    = 0.1713852
MJSWG   = 0.1713852
PRDSW   = 112.8875816
LKETA   = 1.728324E-3
)
```

With 32 size bins and 4 corners, this model has 15,200 model parameters !

# How many models of the MOSFET do we have?

Switch-level model (2)

Square-law model

Square-law model (with  $\lambda$  and bulk additions)

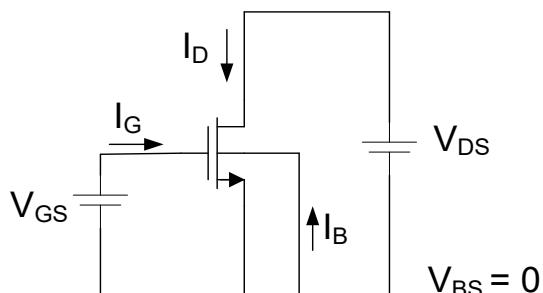
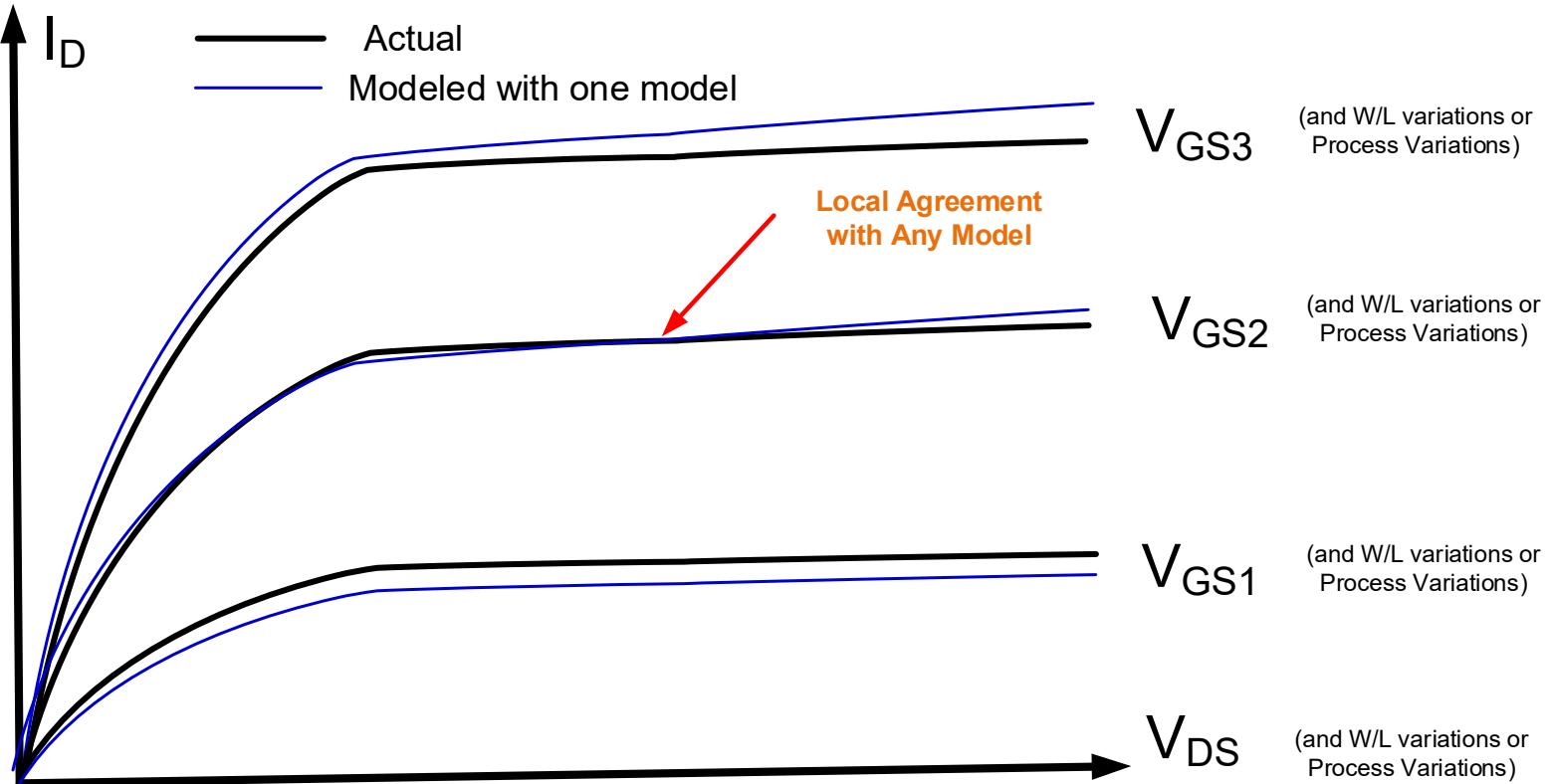
$\alpha$ -law model (with  $\lambda$  and bulk additions)

BSIM model

BSIM model (with binning extensions)

BSIM model (with binning extensions and process corners)

# The Modeling Challenge



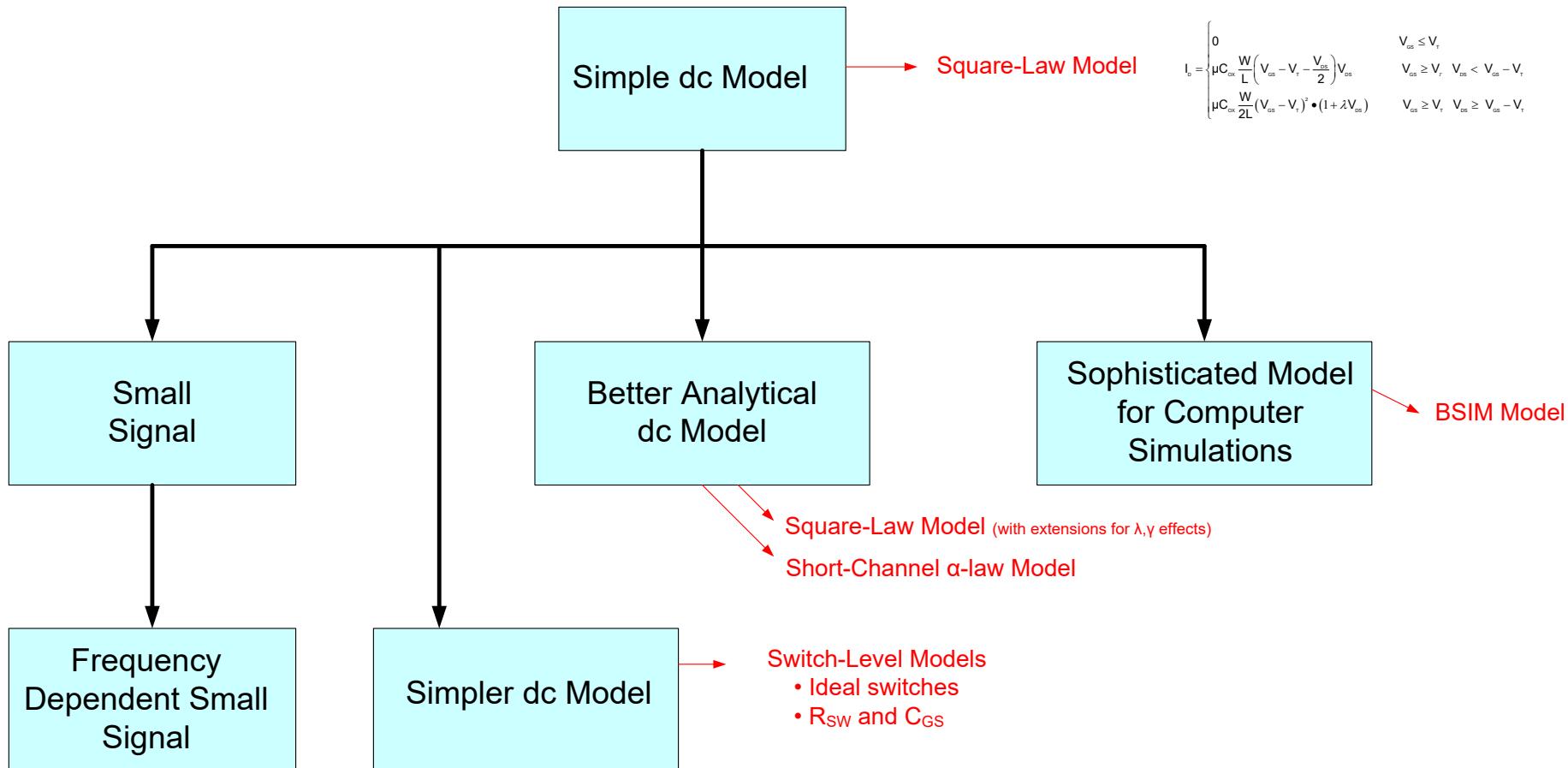
$$I_D = f_1(V_{GS}, V_{DS})$$

$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

Difficult to obtain analytical functions that accurately fit actual devices over bias, size, and process variations

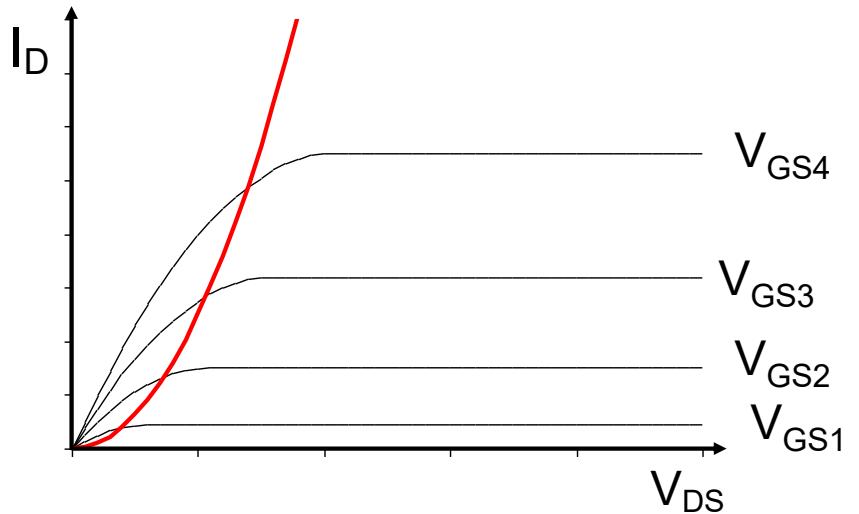
# Model Status



In the next few slides, the models we have developed will be listed and reviewed

- Square-law Model
- Switch-level Models
- Extended Square-law model
- Short-channel model
- BSIM Model
- BSIM Binning Model
- Corner Models

# Square-Law Model

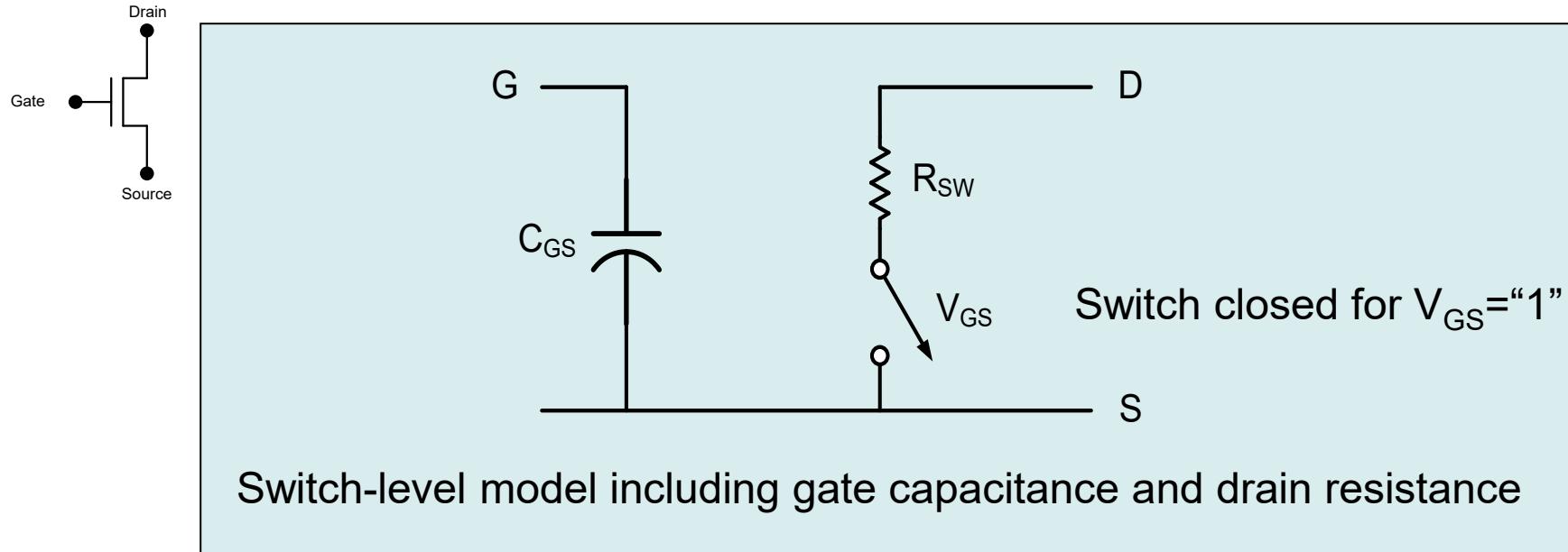


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

Model Parameters :  $\{\mu, C_{ox}, V_{T0}\}$

Design Parameters :  $\{W, L\}$  but only one degree of freedom  $W/L$

# Switch-Level Models



$C_{GS}$  and  $R_{SW}$  dependent upon device sizes and process

For minimum-sized devices in a 0.5 $\mu$  process

$$C_{GS} \cong 1.5\text{fF} \quad R_{sw} \cong \begin{cases} 2\text{K}\Omega & \text{n-channel} \\ 6\text{K}\Omega & \text{p-channel} \end{cases}$$

Considerable emphasis will be placed upon device sizing to manage  $C_{GS}$  and  $R_{SW}$

Model Parameters :  $\{C_{GS}, R_{SW}\}$

# Extended Square-Law Model

$$I_G = 0$$

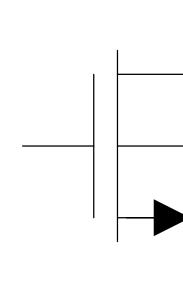
$$I_B = 0$$

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \bullet (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$V_T = V_{T0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

Model Parameters :  $\{\mu, C_{ox}, V_{T0}, \phi, \gamma, \lambda\}$

Design Parameters :  $\{W, L\}$  but only one degree of freedom W/L



# Short-Channel Model

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^\alpha & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \end{cases}$$

$\alpha$  is the velocity saturation index,  $2 \geq \alpha \geq 1$

Channel length modulation ( $\lambda$ ) and bulk effects can be added to the velocity Saturation as well

# BSIM model

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVT0W   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN    = 1
+LLN    = 1
+LWL    = 0
+CGDO   = 2.32E-10
+CJ      = 4.282017E-4
+CJSW   = 3.034055E-10
+CJSWG  = 1.64E-10
+CF      = 0
+PK2    = -0.0289036
*
TNOM    = 27
NCH     = 1.7E17
K2      = -0.09255
W0      = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA      = 3.091785E-13
VSAT    = 1.715884E5
B0      = 2.446405E-6
A1      = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW      = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETA0    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW   = 0.8
PBSWG  = 0.8
PVTH0   = 0.0520855
WKETA   = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0   = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB    = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
KT1     = -0.11
UA1    = 4.31E-9
AT      = 3.3E4
WW     = 0
LL     = 0
LWN    = 1
XPART  = 0.5
CGBO   = 1E-9
MJ      = 0.4495867
MJSW   = 0.1713852
MJSWG  = 0.1713852
PRDSW  = 112.8875816
LKETA   = 1.728324E-3
)
*)
```

Note this model has 95 model parameters !

# BSIM Binning Model

- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVT0W   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN    = 1
+LLN    = 1
+LWL    = 0
+CGDO   = 2.32E-10
+CJ      = 4.282017E-4
+CJSW   = 3.034055E-10
+CJSWG  = 1.64E-10
+CF      = 0
+PK2    = -0.0289036
TNOM     = 27
NCH      = 1.7E17
K2       = -0.09255
W0       = 1.041146E-8
DVT1W   = 0
DVT1    = 0.4232931
UA       = 3.091785E-13
VSAT    = 1.715884E5
B0       = 2.446405E-6
A1       = 8.18159E-7
PRWG    = 0.0328586
WINT    = 2.443677E-7
XW       = 0
VOFF    = -1.493503E-4
CDSC    = 2.4E-4
ETA0    = 2.342963E-3
PCLM    = 2.5941582
PDIBLCB = -0.0431505
PSCBE2  = 3.238266E-4
UTE     = -1.5
KT2     = 0.022
UC1     = -5.6E-11
WLN     = 1
WWL     = 0
LW      = 0
CAPMOD  = 2
CGSO    = 2.32E-10
PB      = 0.9317787
PBSW   = 0.8
PBSWG  = 0.8
PVTH0   = 0.0520855
WKETA  = -0.0237483
LEVEL   = 49
TOX     = 1.42E-8
VTH0   = 0.629035
K3      = 24.0984767
NLX     = 1E-9
DVT2W   = 0
DVT2    = -0.1403765
UB      = 1.702517E-18
A0      = 0.6580918
B1      = 5E-6
A2      = 0.3363058
PRWB   = 0.0104806
LINT    = 6.999776E-8
DWG     = -1.256454E-8
NFACTOR = 1.0354201
CDSCD   = 0
ETAB    = -1.5324E-4
PDIBLC1 = 0.8187825
DROUT   = 0.9919348
PVAG    = 0
KT1     = -0.11
UA1    = 4.31E-9
AT      = 3.3E4
WW     = 0
LL     = 0
LWN    = 1
XPART  = 0.5
CGBO   = 1E-9
MJ      = 0.4495867
MJSW   = 0.1713852
MJSWG  = 0.1713852
PRDSW  = 112.8875816
LKETA  = 1.728324E-3
)
```

\* With 32 bins, this model has 3040 model parameters !

# BSIM Corner Models

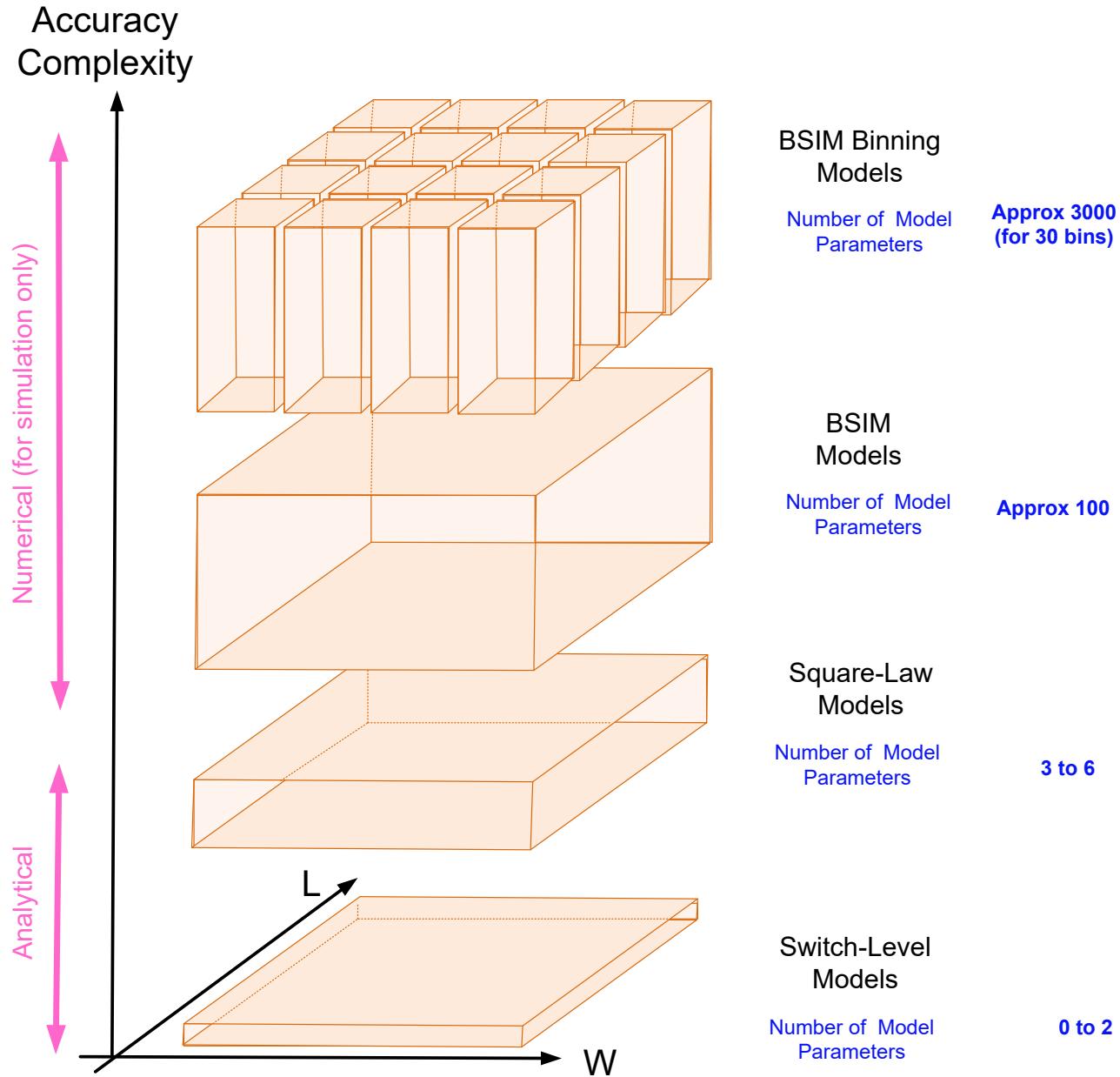
- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS
  - five different BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1
+XJ      = 1.5E-7
+K1      = 0.8976376
+K3B     = -8.2369696
+DVT0W   = 0
+DVT0    = 2.7123969
+U0      = 451.2322004
+UC      = 1.22401E-11
+AGS     = 0.130484
+KETA    = -3.043349E-3
+RDSW    = 1.367055E3
+WR      = 1
+XL      = 1E-7
+DWB     = 3.676235E-8
+CIT     = 0
+CDSCB   = 0
+DSUB    = 0.0764123
+PDIBLC2 = 2.366707E-3
+PSCBE1  = 6.611774E8
+DELT.A  = 0.01
+PRT     = 0
+KT1L    = 0
+UB1     = -7.61E-18
+WL      = 0
+WWN     = 1
+LLN     = 1
+LWL     = 0
+CGDO    = 2.32E-10
+CJ      = 4.282017E-4
+CJSW    = 3.034055E-10
+CJSWG   = 1.64E-10
+CF      = 0
+PK2     = -0.0289036
*T
        TNOM    = 27
        NCH     = 1.7E17
        K2      = -0.09255
        W0      = 1.041146E-8
        DVT1W   = 0
        DVT1    = 0.4232931
        UA      = 3.091785E-13
        VSAT    = 1.715884E5
        B0      = 2.446405E-6
        A1      = 8.18159E-7
        PRWG    = 0.0328586
        WINT    = 2.443677E-7
        XW      = 0
        VOFF    = -1.493503E-4
        CDSC    = 2.4E-4
        ETA0    = 2.342963E-3
        PCLM    = 2.5941582
        PDIBLCB = -0.0431505
        PSCBE2  = 3.238266E-4
        RSH     = 83.5
        UTE     = -1.5
        KT2     = 0.022
        UC1     = -5.6E-11
        WLN     = 1
        WWL     = 0
        LW      = 0
        CAPMOD  = 2
        CGSO    = 2.32E-10
        PB      = 0.9317787
        PBSW    = 0.8
        PBSWG   = 0.8
        PVTH0   = 0.0520855
        WKETA   = -0.0237483
        LEVEL   = 49
        TOX     = 1.42E-8
        VTH0    = 0.629035
        K3      = 24.0984767
        NLX     = 1E-9
        DVT2W   = 0
        DVT2    = -0.1403765
        UB      = 1.702517E-18
        A0      = 0.6580918
        B1      = 5E-6
        A2      = 0.3363058
        PRWB    = 0.0104806
        LINT    = 6.999776E-8
        DWG     = -1.256454E-8
        NFACTOR = 1.0354201
        CDSCD   = 0
        ETAB    = -1.5324E-4
        PDIBLC1 = 0.8187825
        DROUT   = 0.9919348
        PVAG    = 0
        MORMOD  = 1
        KT1     = -0.11
        UA1     = 4.31E-9
        AT      = 3.3E4
        WW     = 0
        LL      = 0
        LWN     = 1
        XPART   = 0.5
        CGBO    = 1E-9
        MJ      = 0.4495867
        MJSW    = 0.1713852
        MJSWG   = 0.1713852
        PRDSW   = 112.8875816
        LKETA   = 1.728324E-3
)
)
```

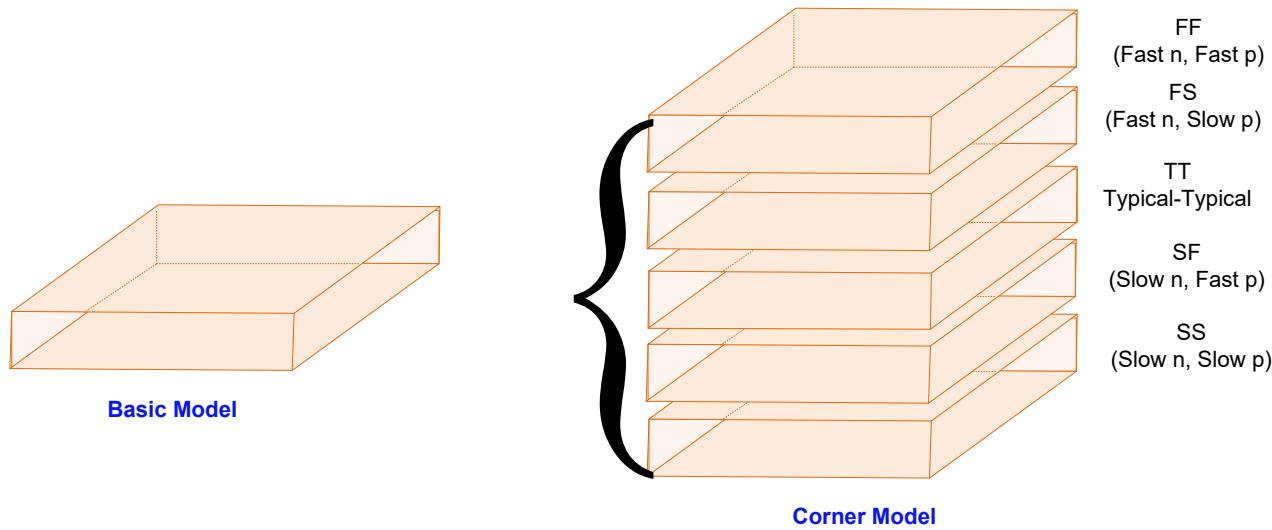
TT: typical-typical  
FF: fast n, fast p  
FS: fast n, slow p  
SF: slow n, fast p  
SS: slow n, slow p

With 4 corners, this model has 475 model parameters !

# Hierarchical Model Comparisons



# Corner Models



Applicable at any level in model hierarchy (same model, different parameters)

Often 4 corners (FF, FS, SF, SS) used but sometimes many more

Designers must provide enough robustness so good yield at all corners



**Stay Safe and Stay Healthy !**

End of Lecture 17